



I³N *Innovative
Integrated
Instrumentation
for Nanoscience*



**POLITECNICO
MILANO 1863**

High Resolution Electronic Measurements in Nano-Bio Science

Measuring currents below 4K

Cryogenic electronics

Giorgio Ferrari

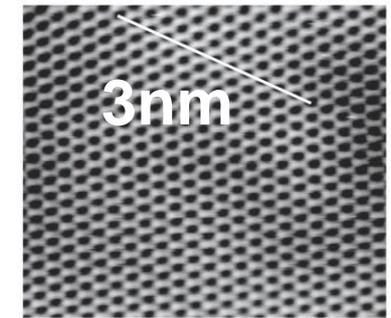
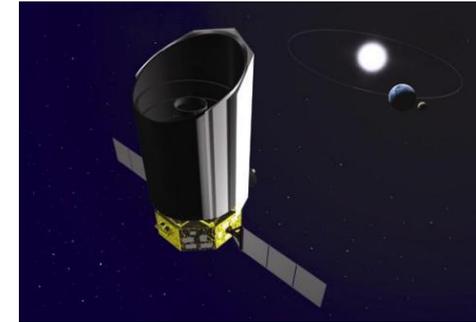
Milano, June 2023

Outline

- Spin detection using room temperature instrumentation
- Cryogenic electronics
 - Challenges
 - Design rules
- Examples

Motivation for cryogenic electronics

- Space applications
 - $T_{\text{deep space}} \approx 3\text{K}$
 - mid- and far-infrared detectors require temperature below 5K
- Cryogenic STM/SPM systems
 - Less thermal fluctuations and drift

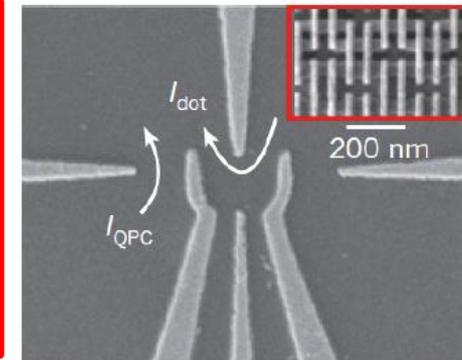


Rev. Sci. Instr.,
121101 (2010)

graphene, profile $\pm 20\text{pm}$

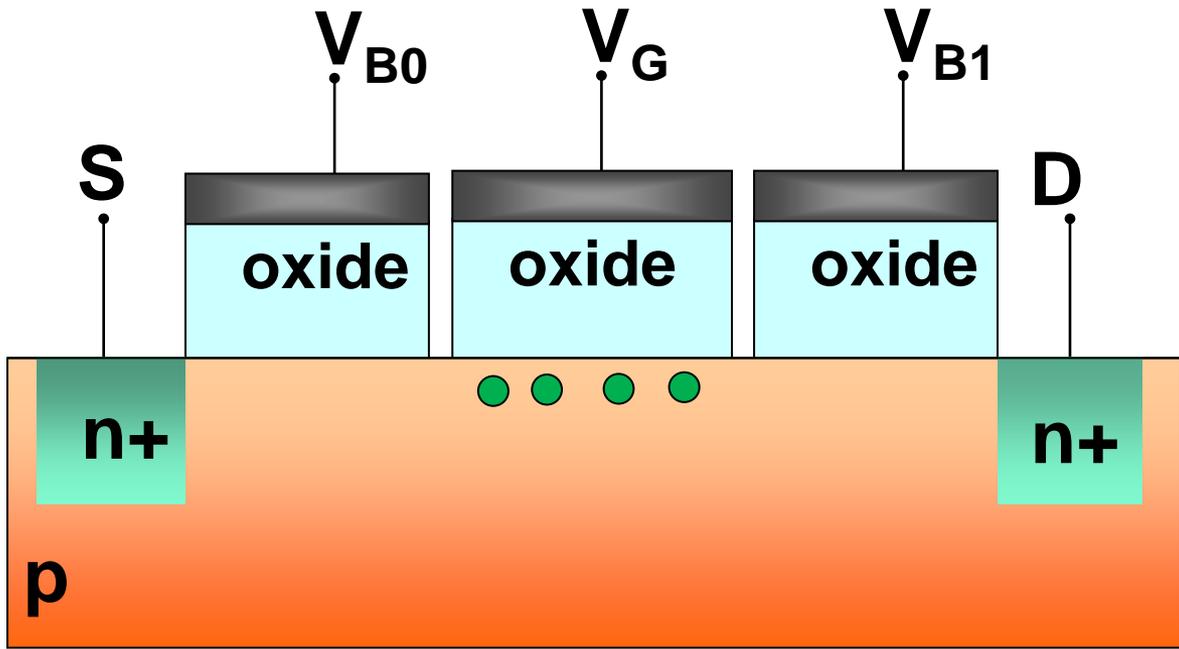
- Quantum devices and quantum computing
 - Low temperature for reducing thermal energy
 - Superconductors

Readout and characterization of spin qubits



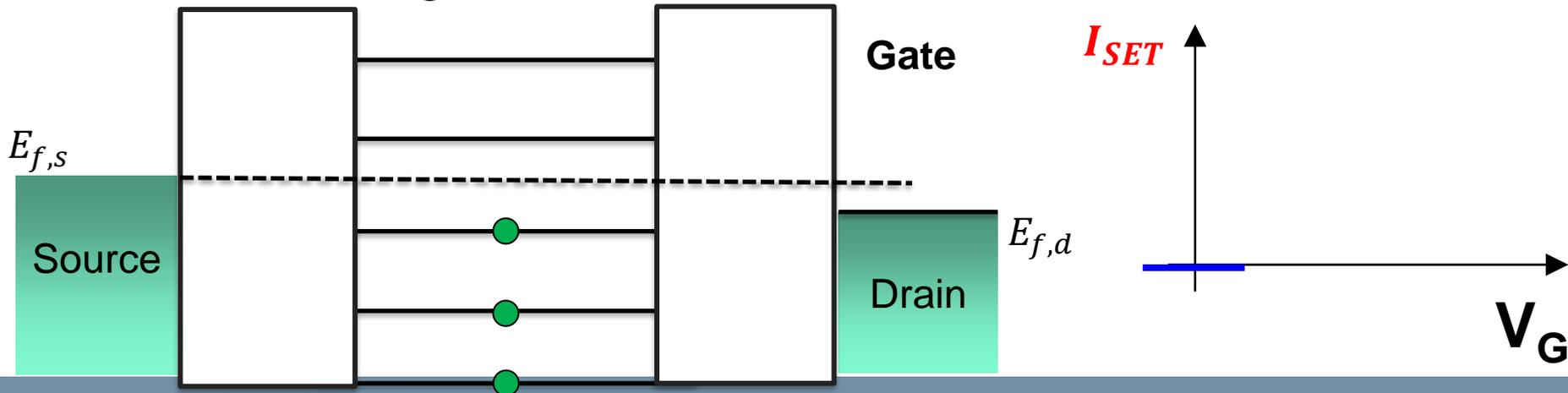
Nature 479, 345 (2011)

Single-Electron Transistor (SET)

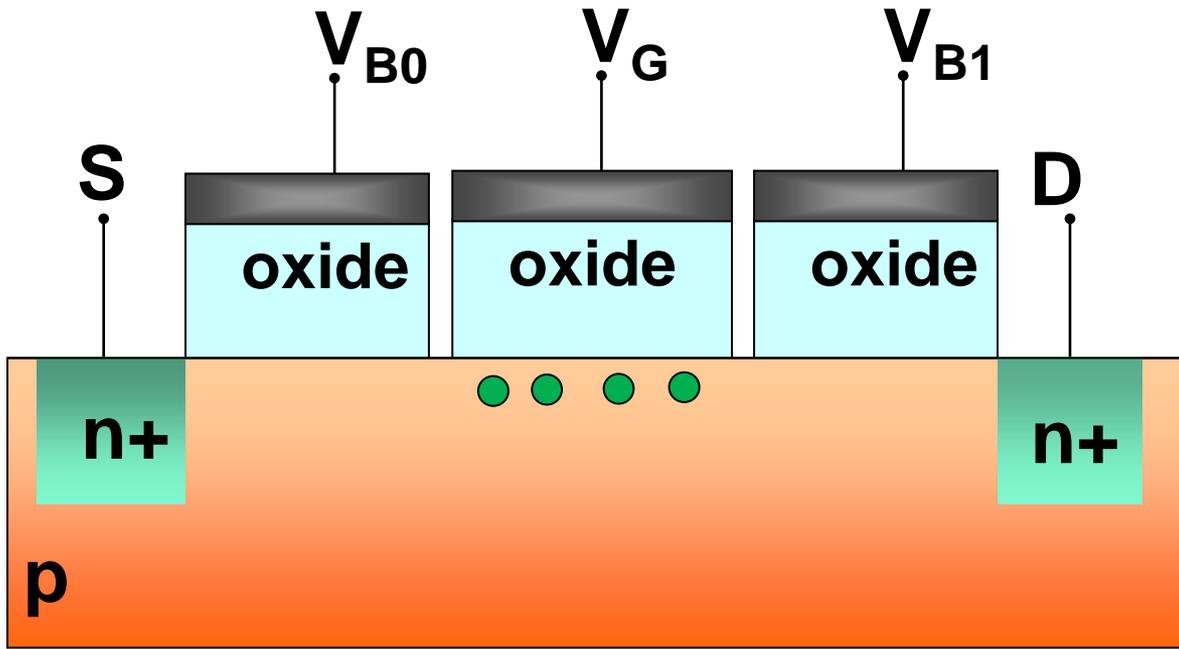


V_{B0} , V_{B1} biased to have an energy barrier for the electrons
The energy barrier is thin enough to allow tunneling

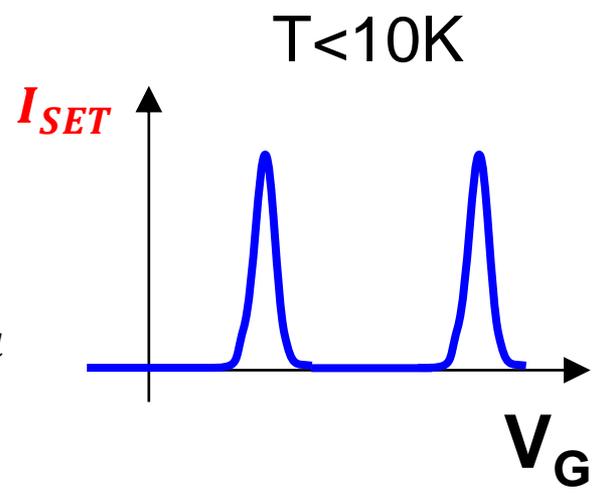
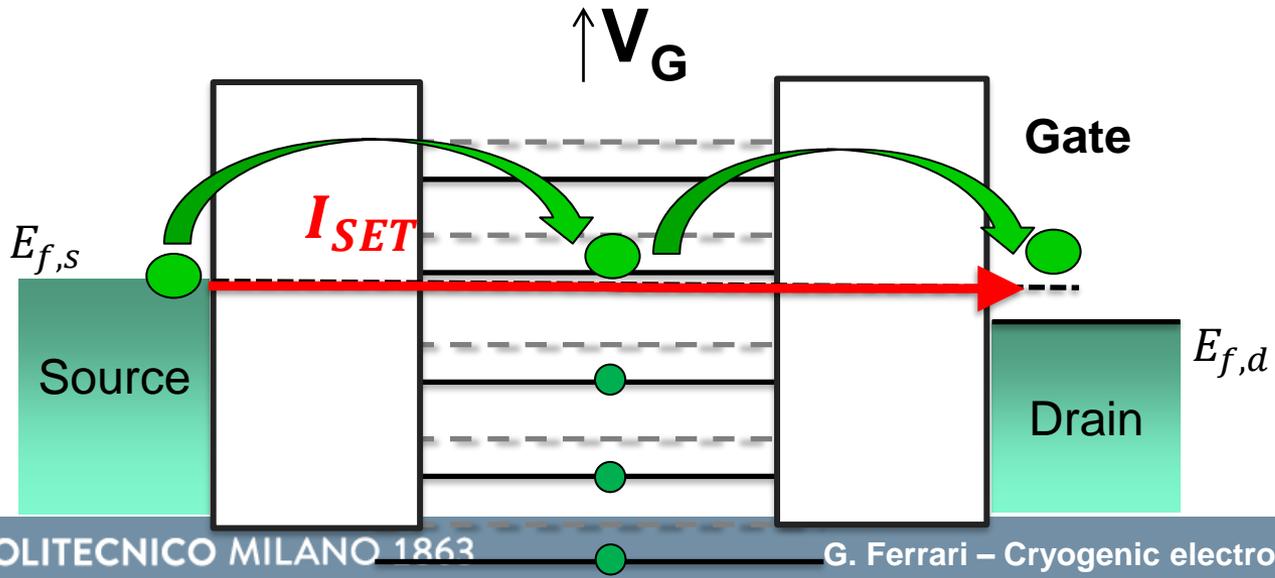
V_G controls the energy levels of the island



Single-Electron Transistor (SET)

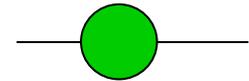


V_{B0} , V_{B1} biased to have an energy barrier for the electrons
 The energy barrier is thin enough to allow tunneling

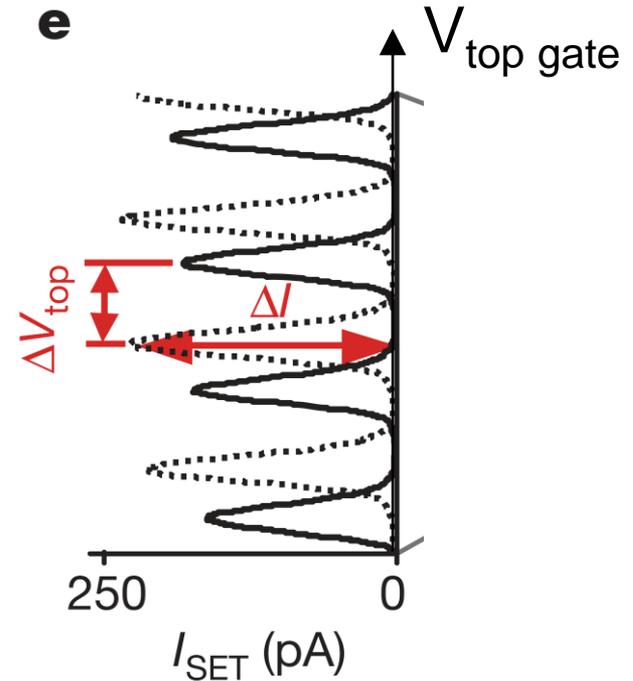
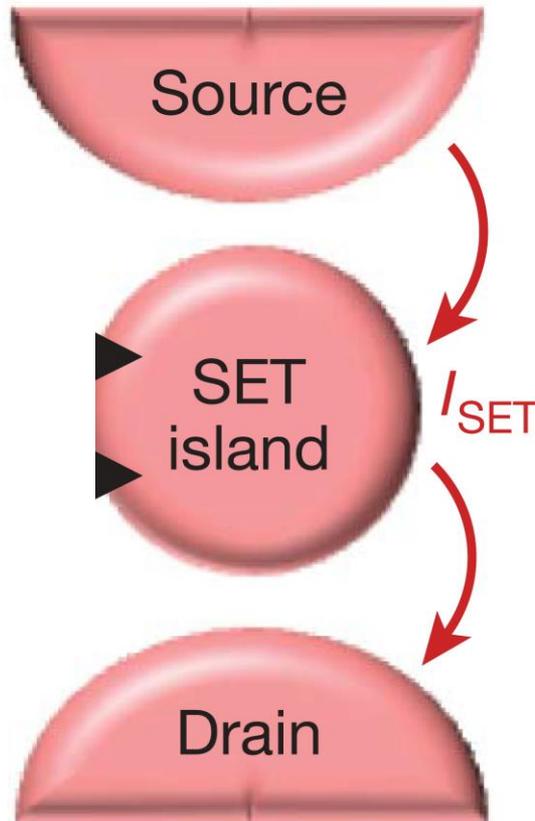


SET-based single-charge detector

see Prati's lesson



Single electron (donor)

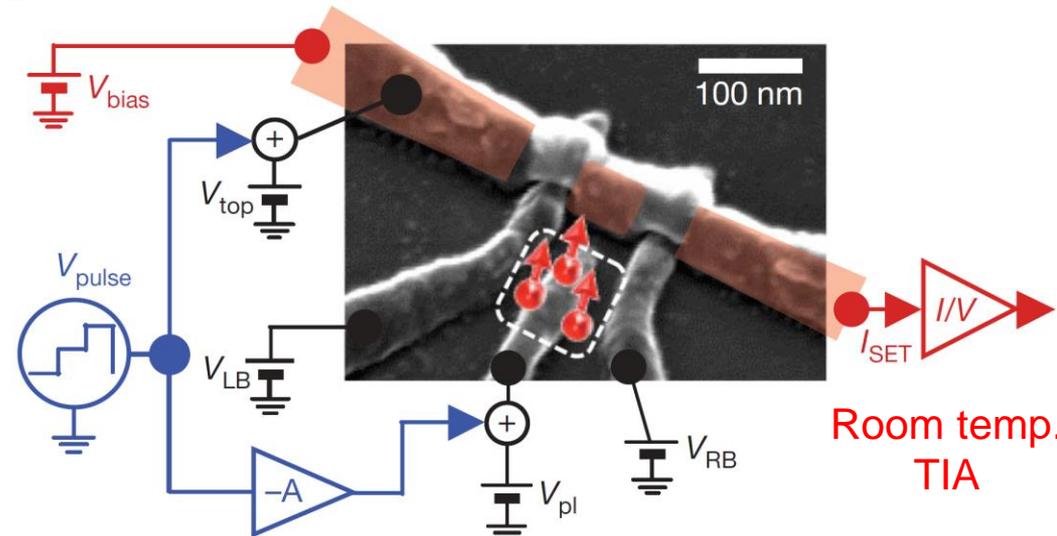
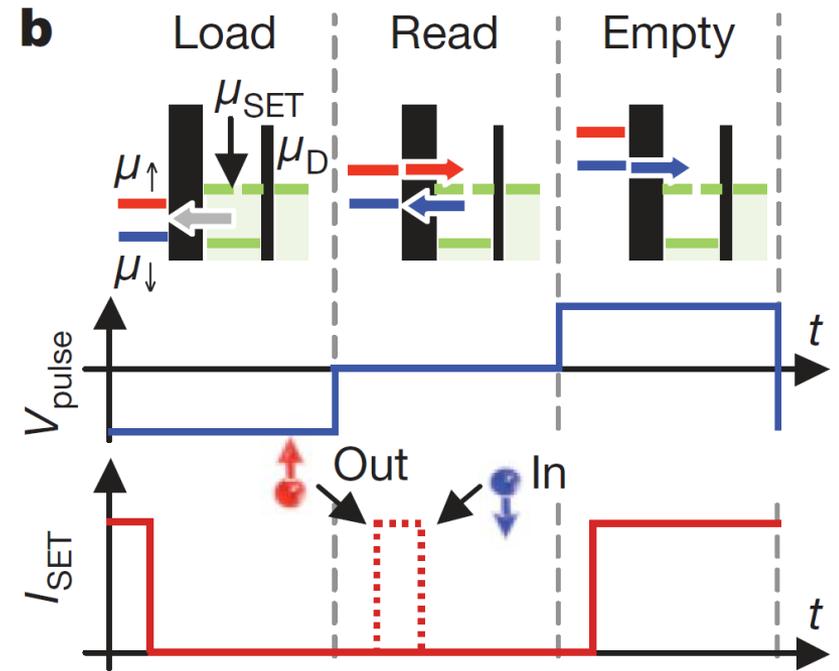
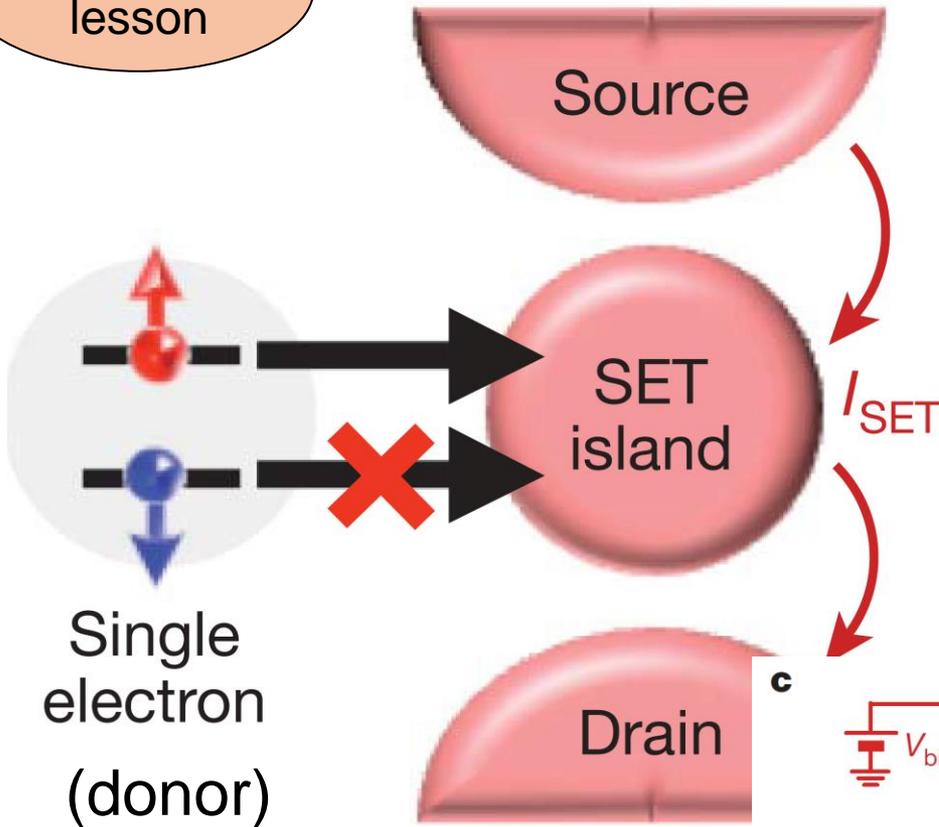


ΔV_{top} : voltage shift of the SET island given by the charge state of the donor

A. Morello, et al. *Nature*, no. 7316, pp. 687–91, 2010, doi: 10.1038/nature09392.

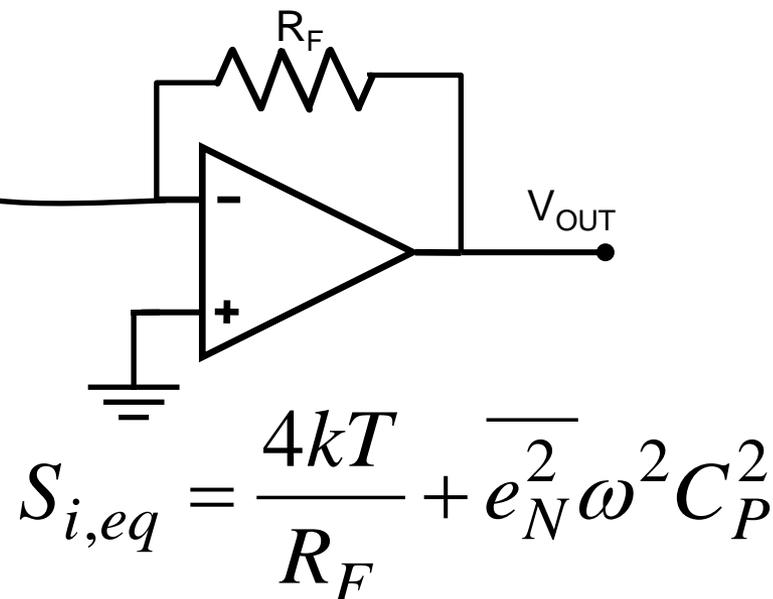
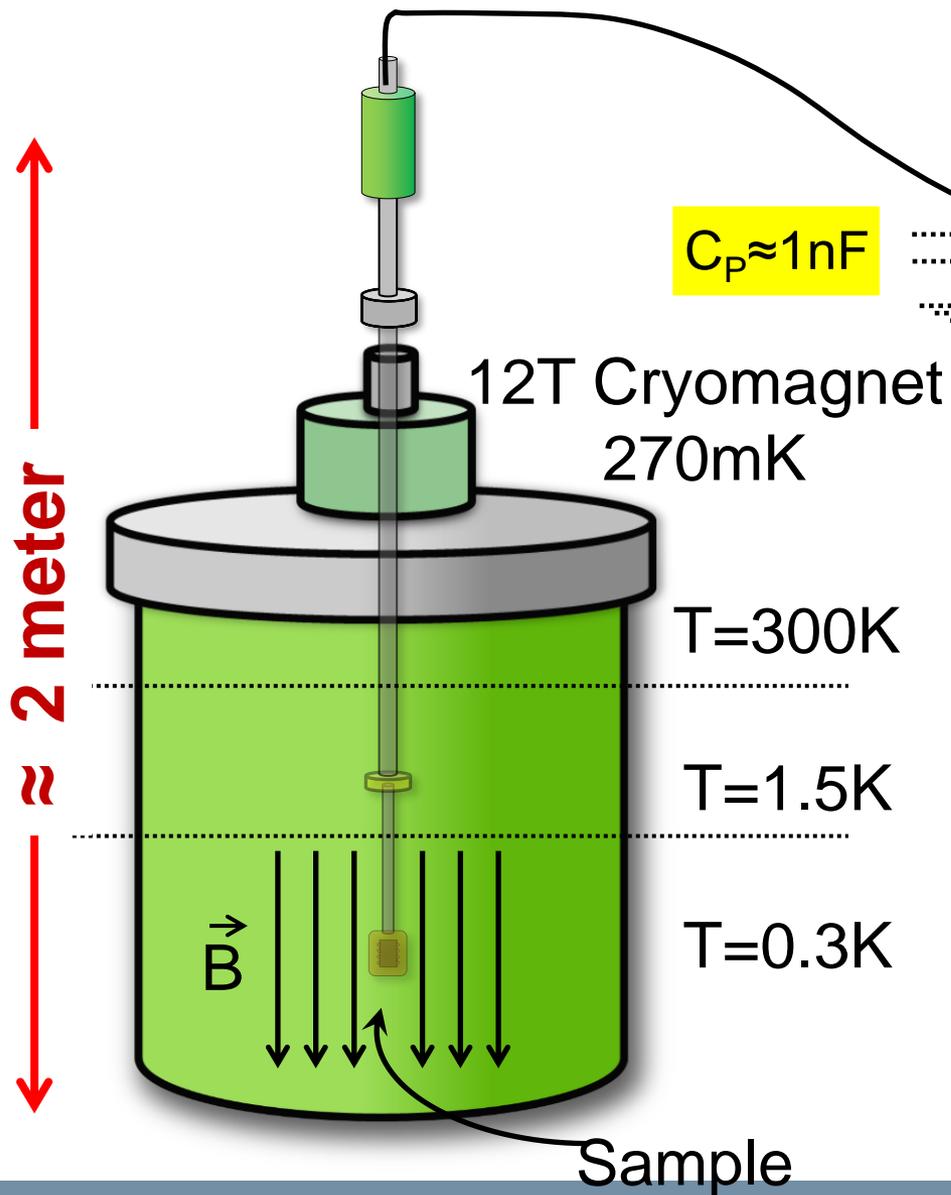
Spin state detection: spin-to-charge conversion

see Prati's lesson



A. Morello, et al. *Nature*, no. 7316, pp. 687–91
2010, doi: 10.1038/nature09392.

Experimental set-up to study quantum devices



$$S_{i,eq} = \frac{4kT}{R_F} + \overline{e_N^2} \omega^2 C_P^2$$

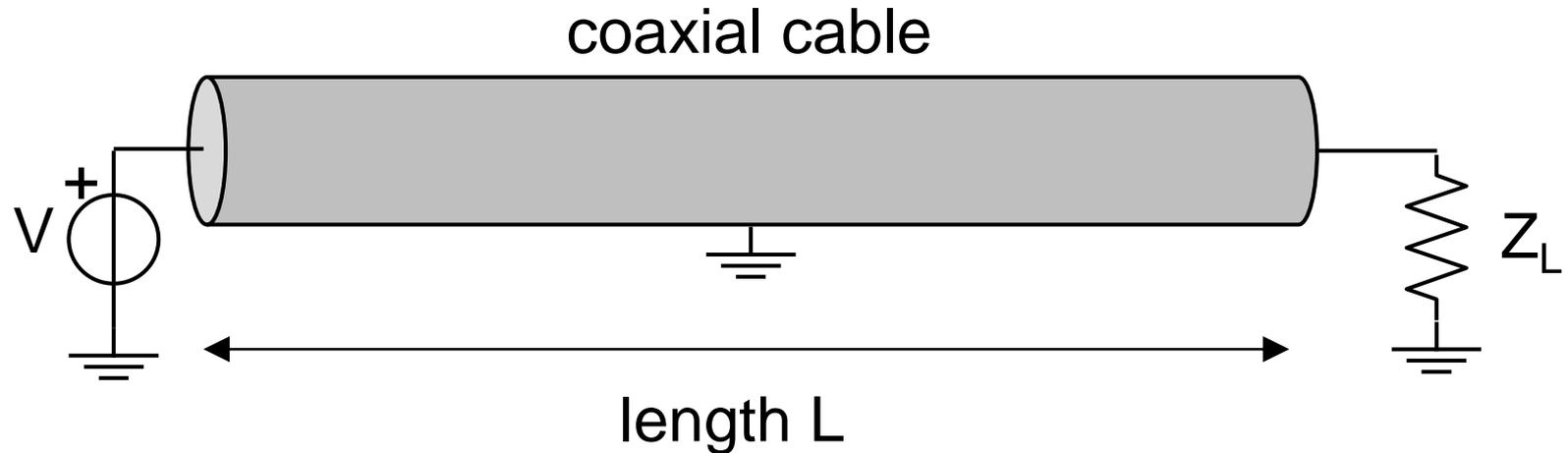
$$I_{RMS} = \frac{2\pi e_N C_P B W^{3/2}}{\sqrt{3}}$$

$$B W = \sqrt{\frac{GBWP}{10 \cdot 2\pi R_f C_P}}$$

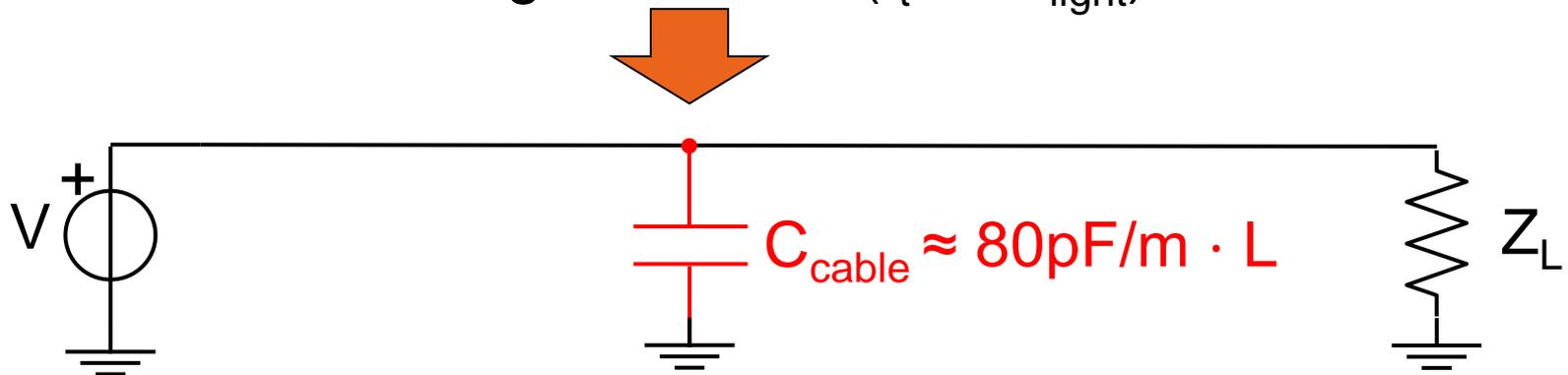
C_P reduces performances

How to avoid being penalized by a long cable?

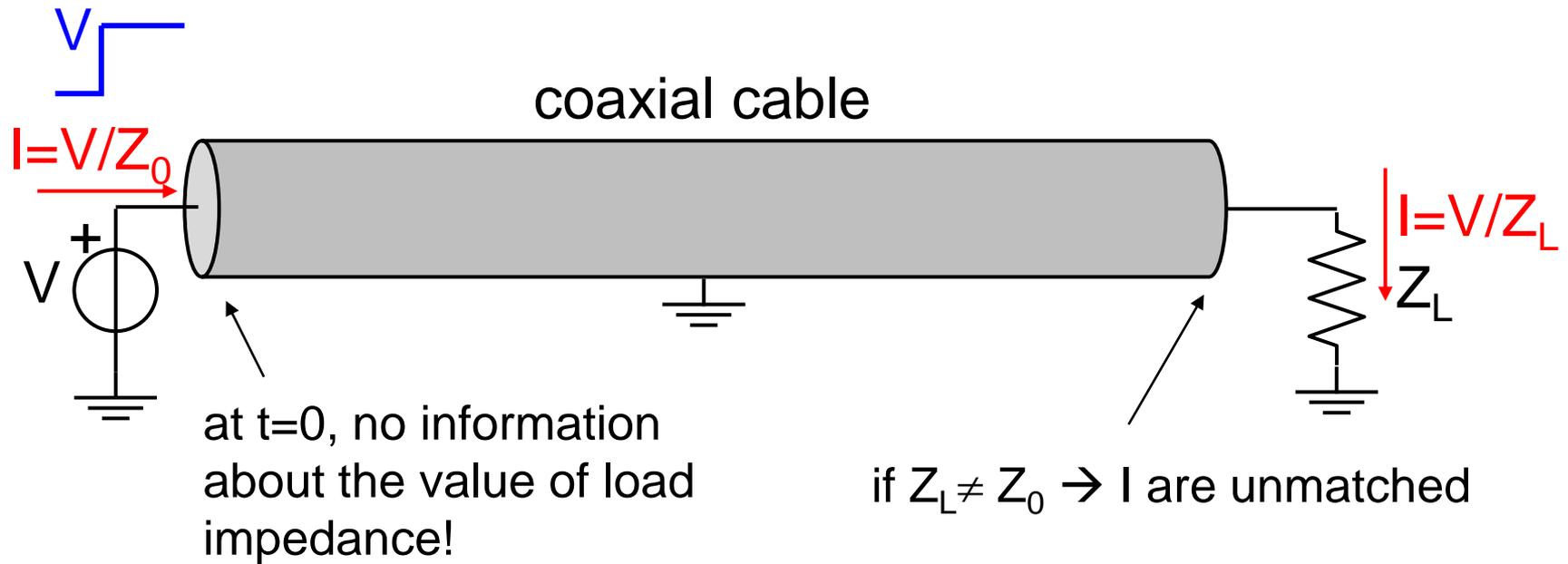
Measuring an impedance using the properties of the cable:



If V changes slowly compared to the transit time of the electromagnetic wave ($t_t = L/v_{\text{light}}$):

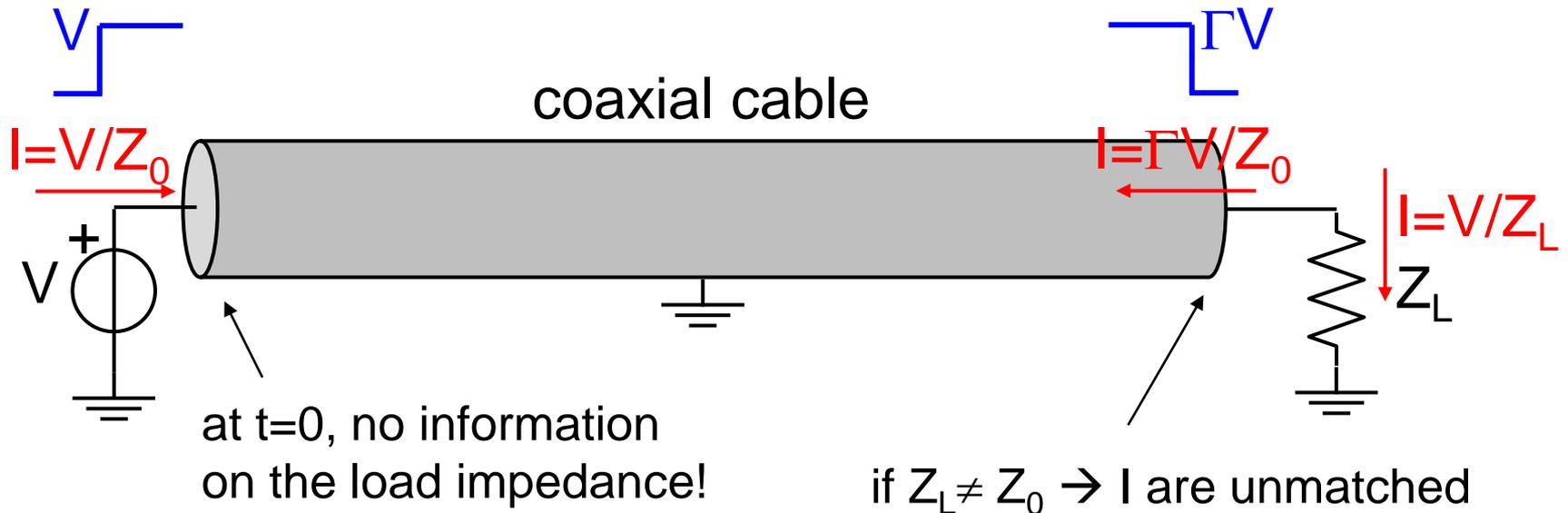


Transmission line



Z_0 = characteristic impedance
of the cable, usually 50Ω

Transmission line



Z_0 = characteristic cable impedance, usually 50Ω

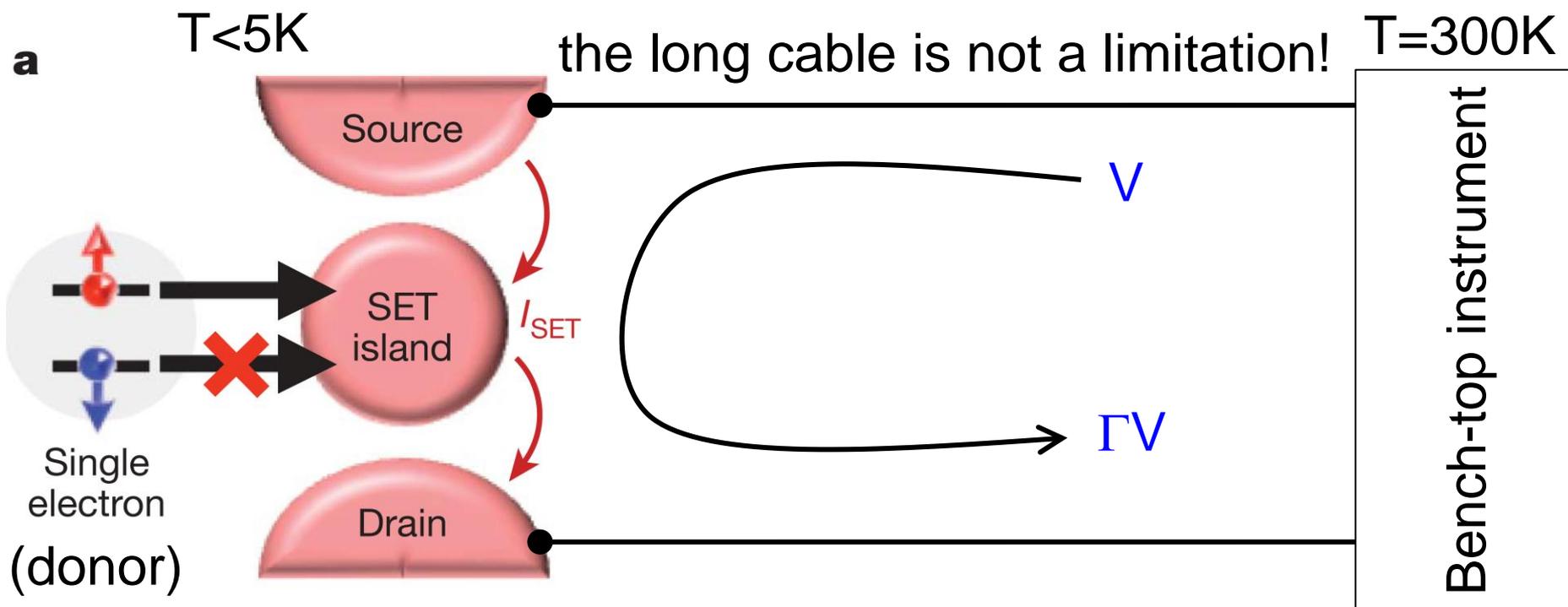
The reflected wave is related to the load impedance!

a reflected wave is created!

$$\Gamma = \frac{Z_L - Z_0}{Z_L + Z_0}$$

reflection coefficient

Radio-frequency spin readout

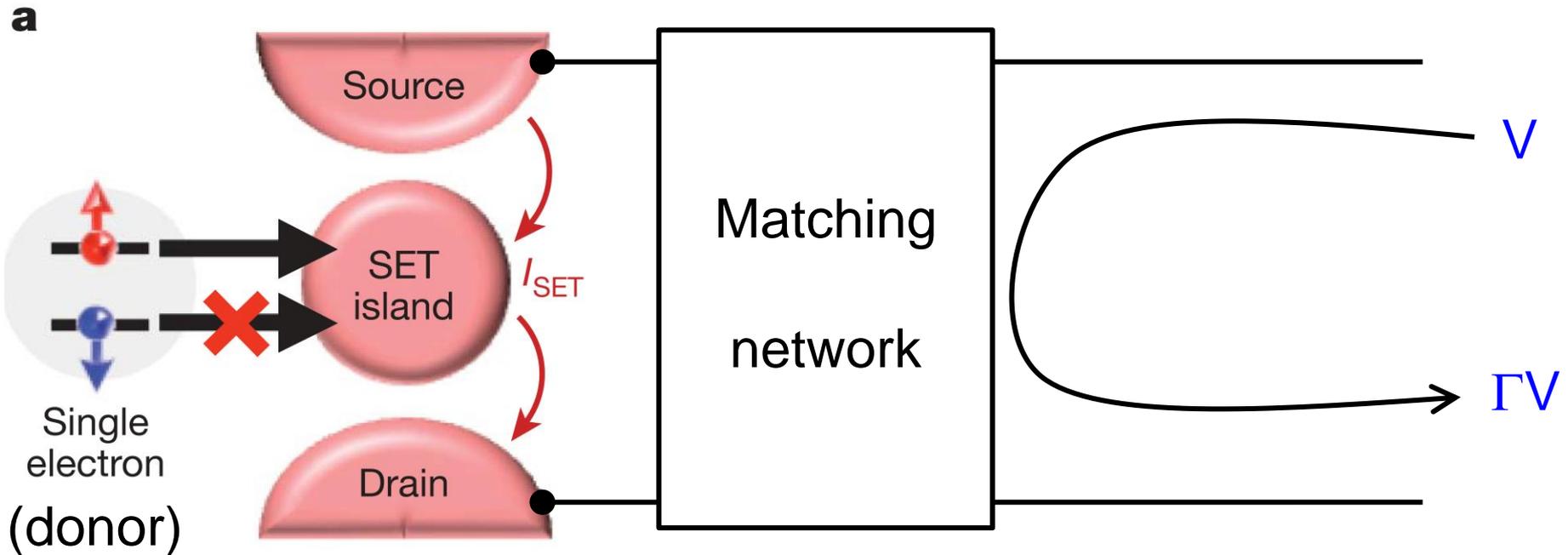


SET resistance depends on the donor charge that, in turn, depends on the spin

$$\Gamma = \frac{R_{SET} - Z_0}{R_{SET} + Z_0}$$

However, $R_{SET} > 25k\Omega$, $Z_0 \approx 50\Omega$ ➔ limited sensitivity

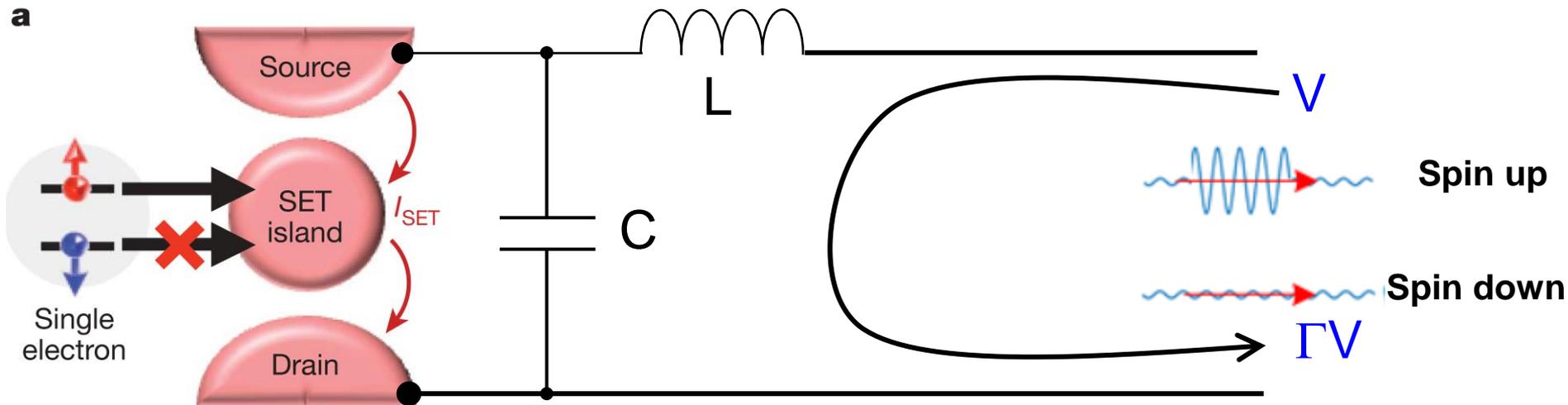
Matching network



SET resistance depends by the donor charge

Passive network to match the high resistance of the SET to the $Z_0=50\Omega$ of the line

Matching network

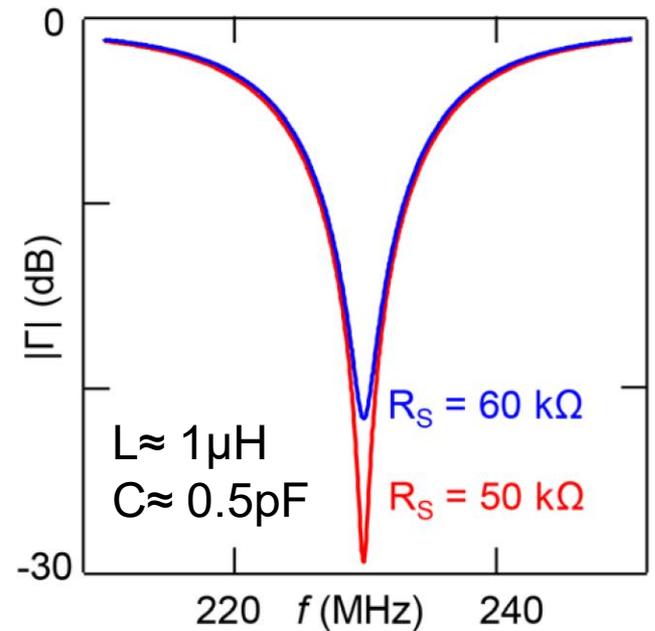


$$Z_L = R_{SET} \frac{1 + \frac{sL}{R_{SET}} + s^2 LC}{1 + sCR_{SET}}$$

$$\omega_{res} = \frac{1}{\sqrt{LC}}$$

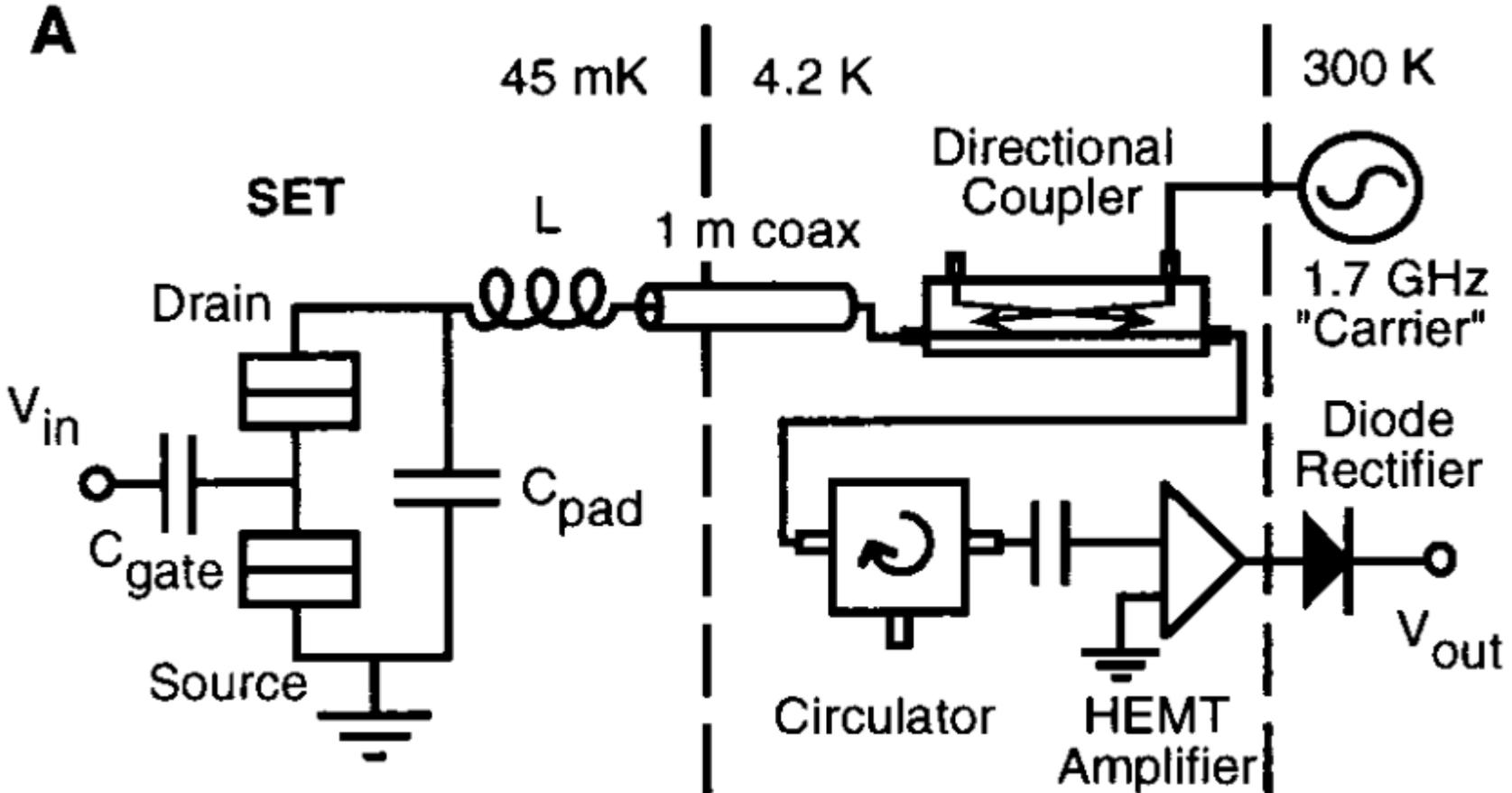
$$Z_L(\omega_{res}) = \frac{L}{CR_{SET}}$$

L, C selected to
have $Z_L(\omega_{res}) \approx Z_0$



Readout based on RF reflectometry

R. Schoelkopf, et al. "The radio-frequency single-electron transistor (RF-SET): A fast and ultrasensitive electrometer," *Science*, vol. 280, no. 5367, pp. 1238–42, May 1998



Reflectometry allows high-sensitivity measurements despite long cables
(similar technique could be applied to the gate of the SET)

Recent review paper: F. Vigneau, et al. *Appl. Phys. Rev.* (2023), doi: 10.1063/5.0088229.

Quantum computer: wiring!

MIT Technology Review

Intelligent Machines

We'd have more
quantum computers if
it weren't so hard to
find the damn cables

by [Martin Giles](#), January 17, 2019

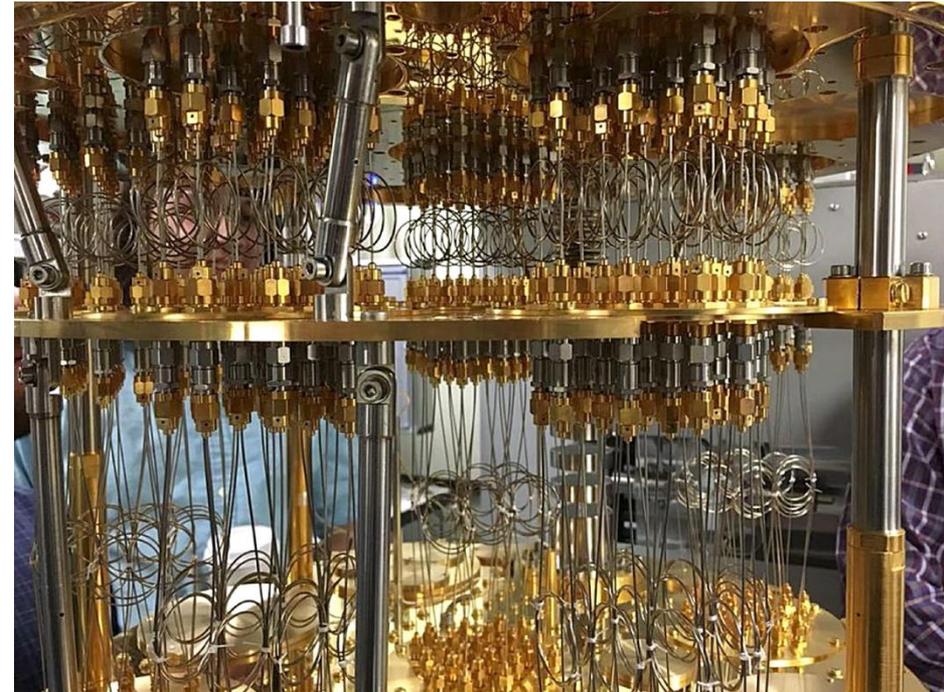
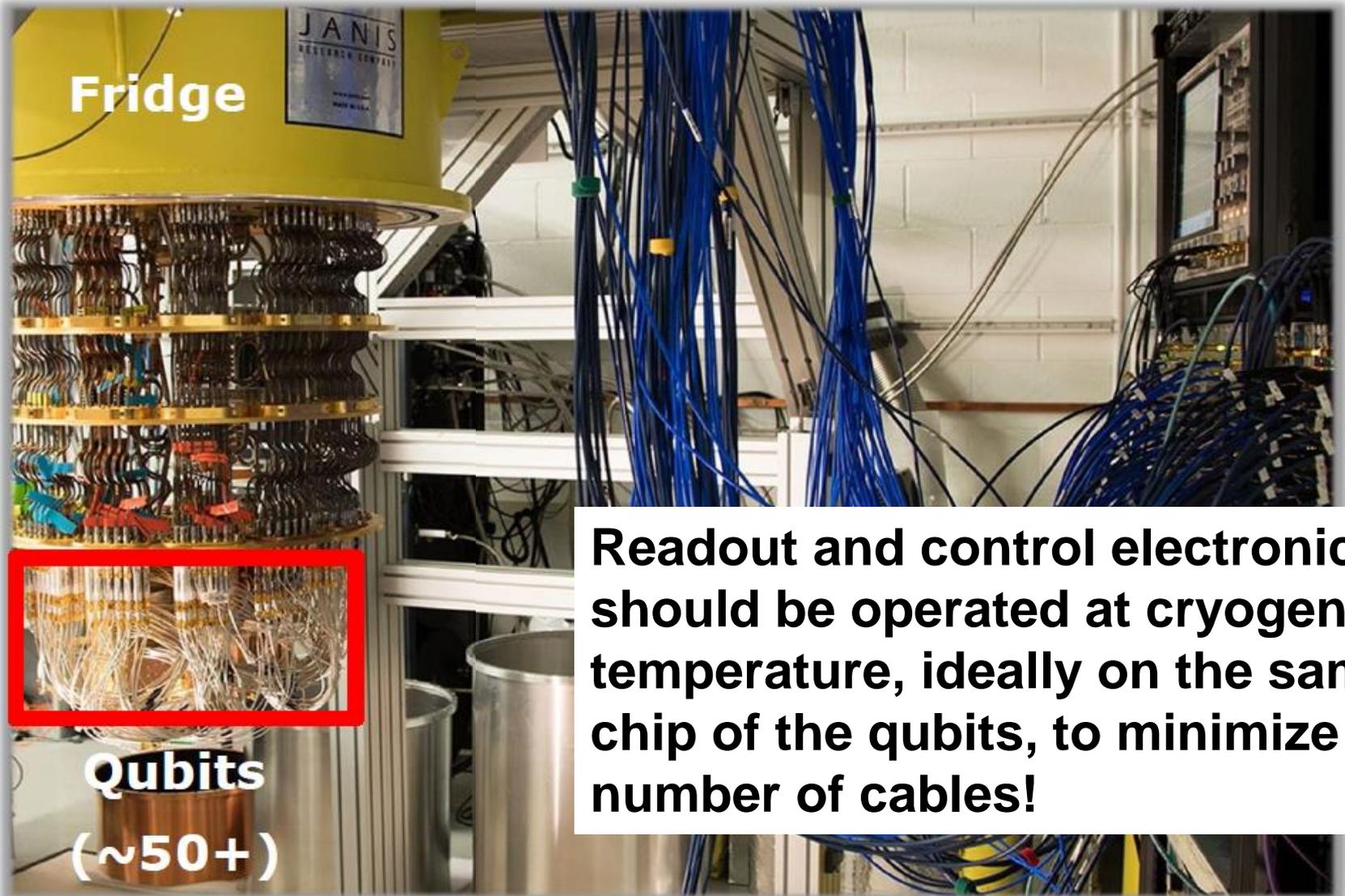


Image: IBM Research

Cables connecting qubits (<4K) to room temperature electronics are a limiting factor!
(≈ 2 coaxial cables /qubit)

Quantum computer: cryogenic electronics!



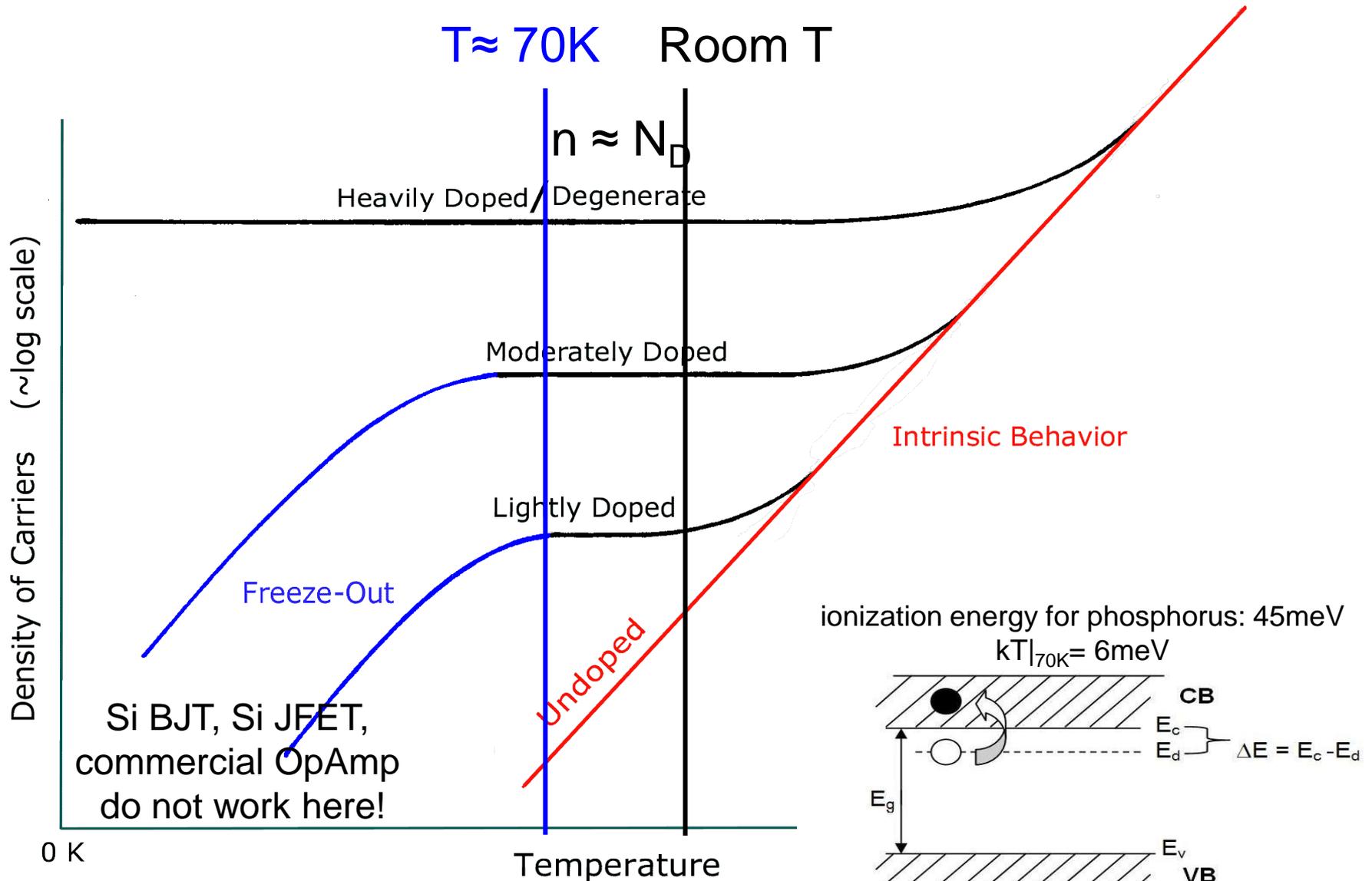
Readout and control electronics should be operated at cryogenic temperature, ideally on the same chip of the qubits, to minimize the number of cables!

[Bardin, ISSCC 2019]

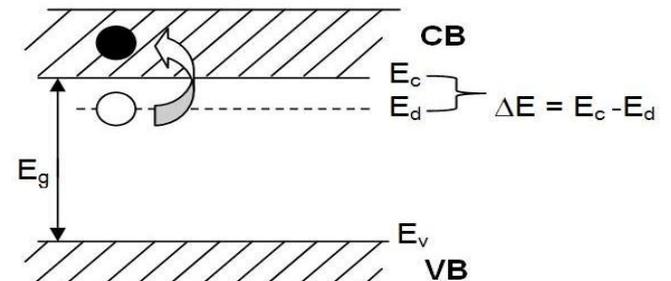
Outline

- Spin detection using room temperature instrumentation
- Cryogenic electronics
 - Challenges
 - Design rules
- Examples

Freeze-out and degenerate semiconductor

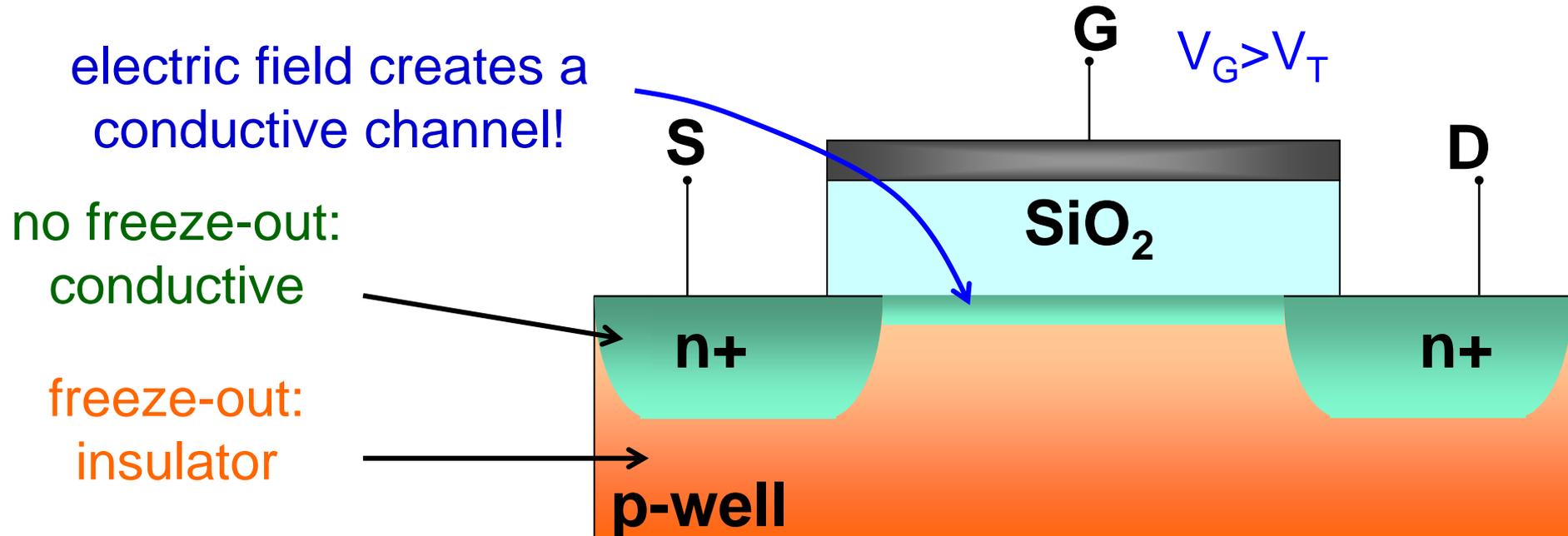


ionization energy for phosphorus: 45meV
 $kT|_{70K} = 6meV$



<http://fog.ccsf.cc.ca.us/~wkaufmyn/>

Electronics below the freeze-out temp.



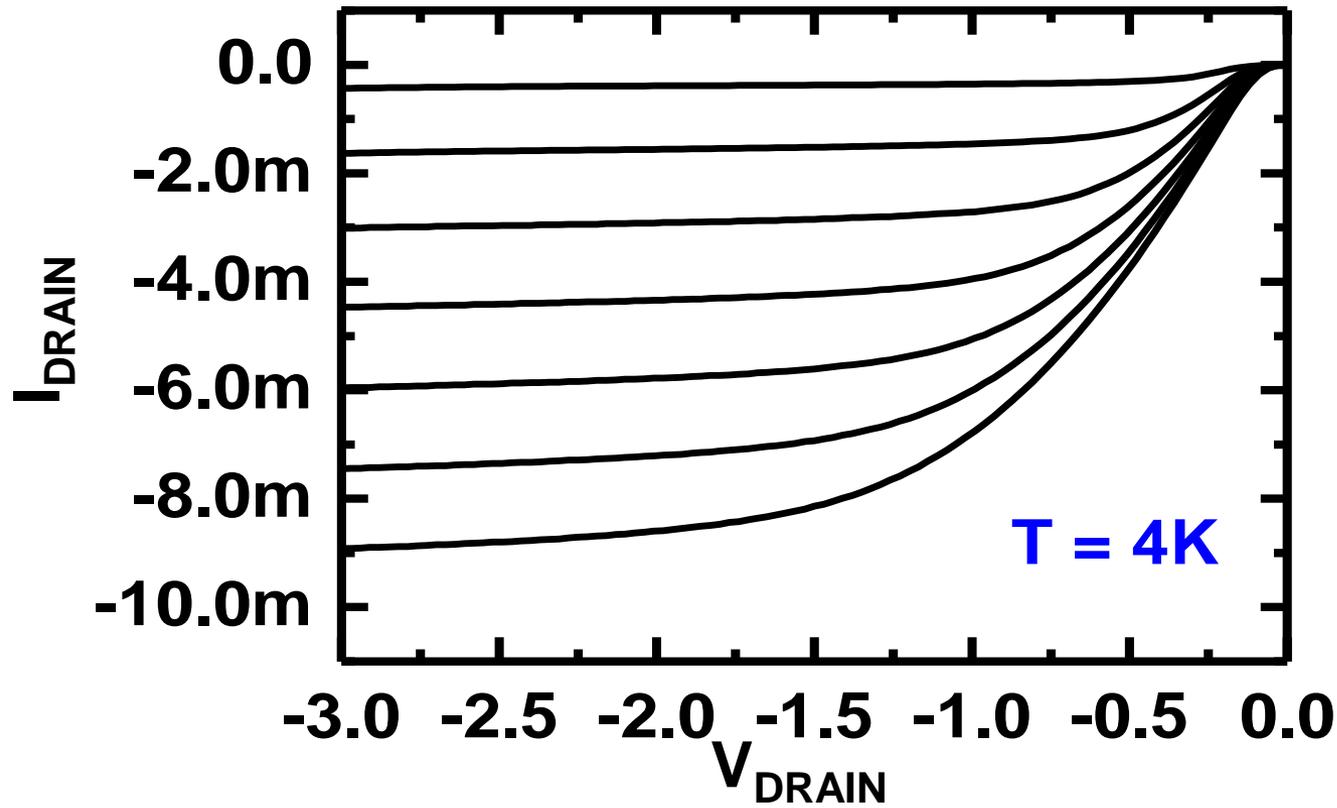
Silicon (standard) MOSFET operates below 40K!

Many GaAs devices operate at cryogenic temperature:
degenerate at 10^{16} cm^{-3}

Limitation: small (and expensive) scale integration

MOSFET operating at 4K

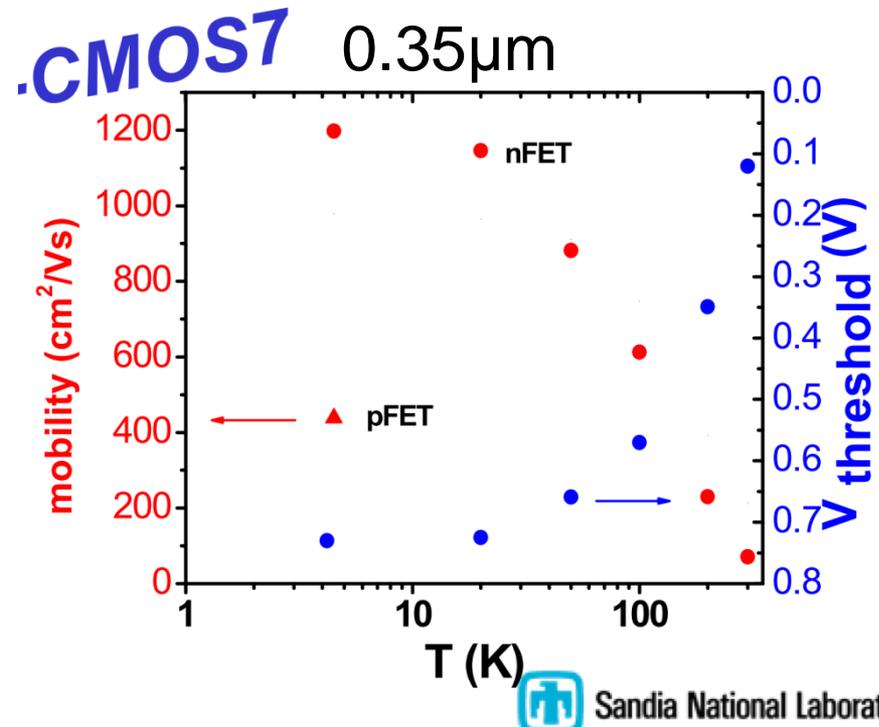
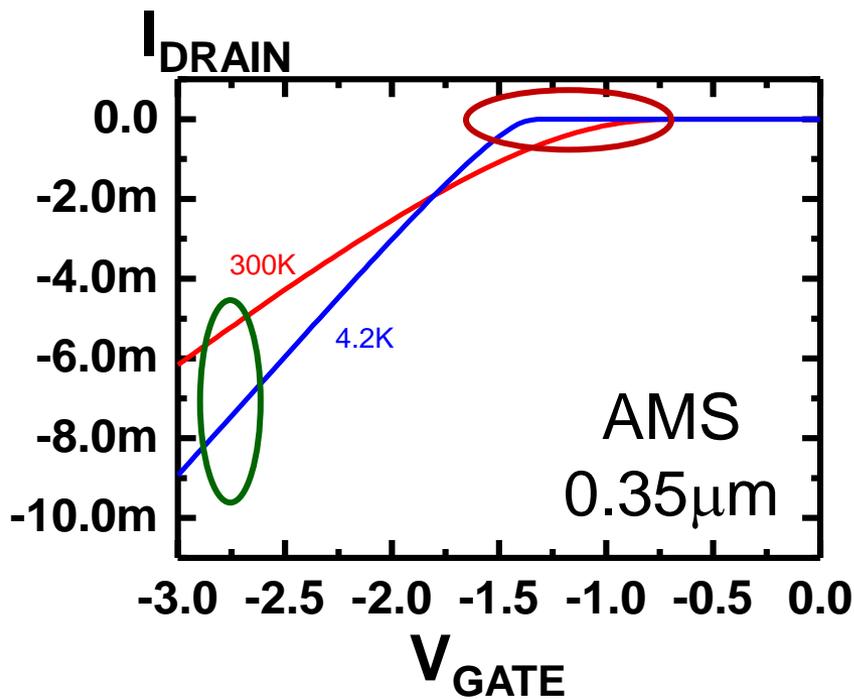
Standard analog CMOS Technology 3.3V, 0.35 μm
PMOS 50 μm / 0.7 μm



very similar to the room temperature behavior!

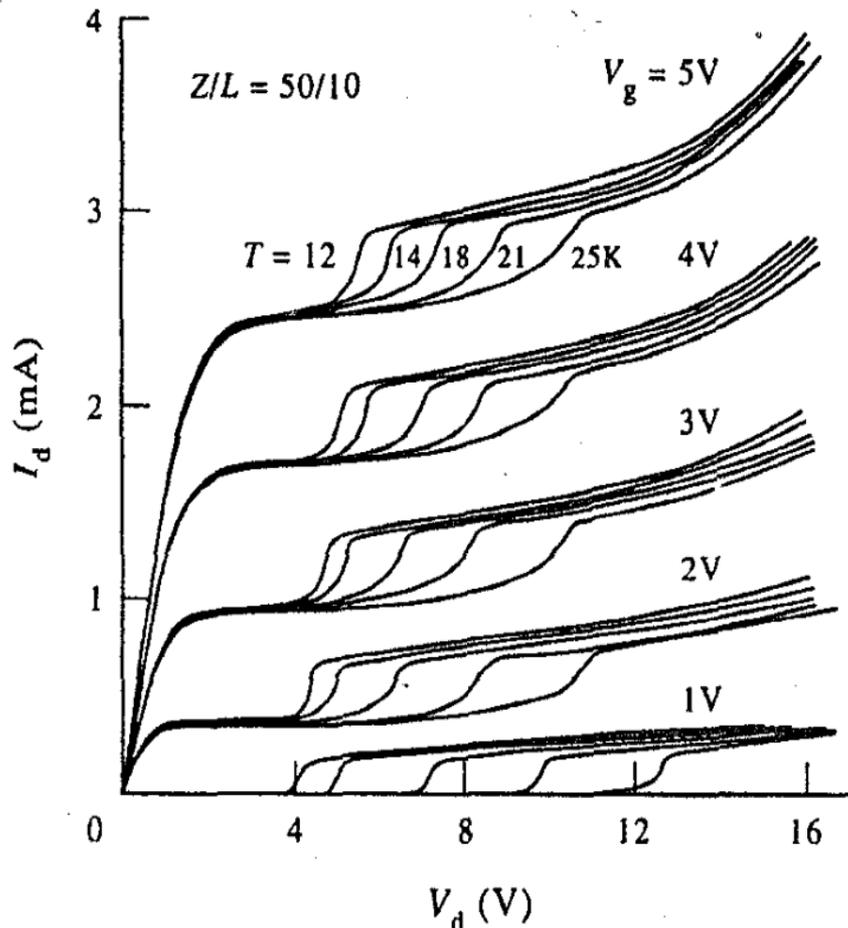
Effects of low temperature

- reduction in electron - phonon scattering
→ increase in carrier mobility
- substrate Fermi level shifts near to E_C (pMOS)
→ increase of the threshold voltage

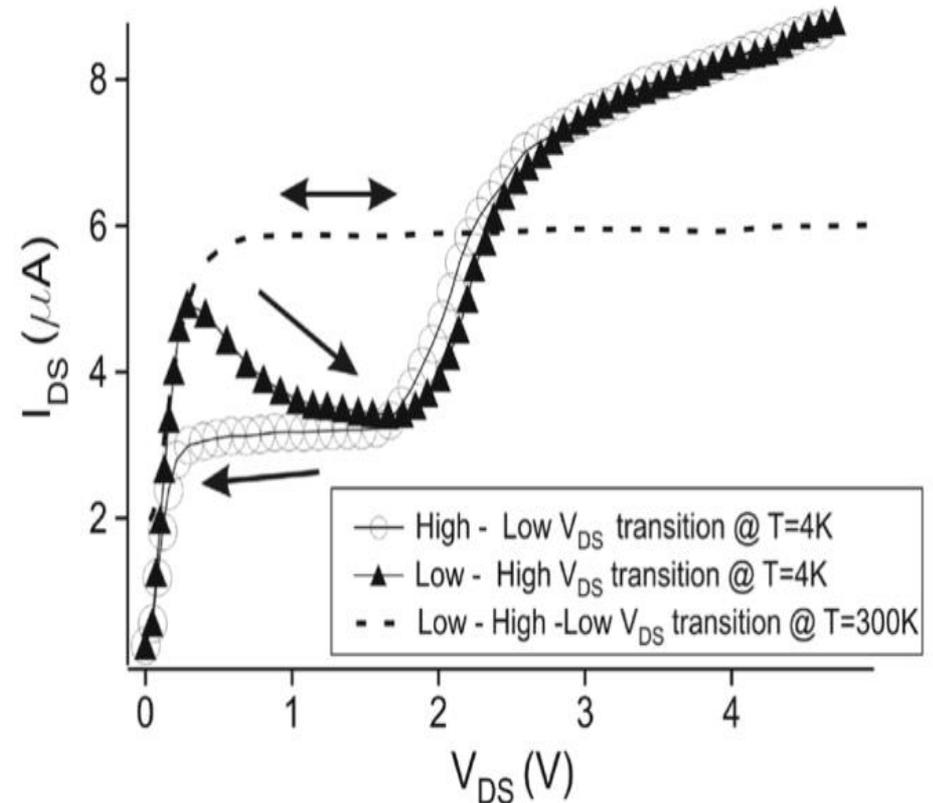


MOSFET operating at 4K: problems

kink effect



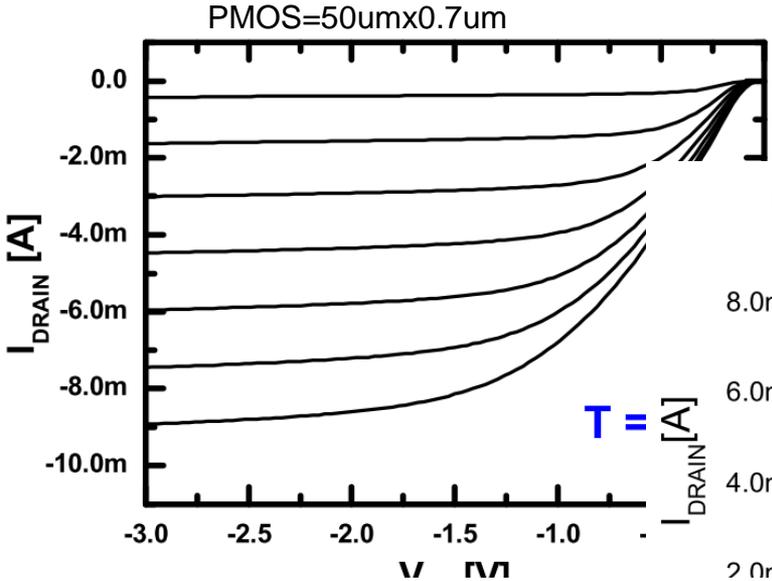
hysteresis



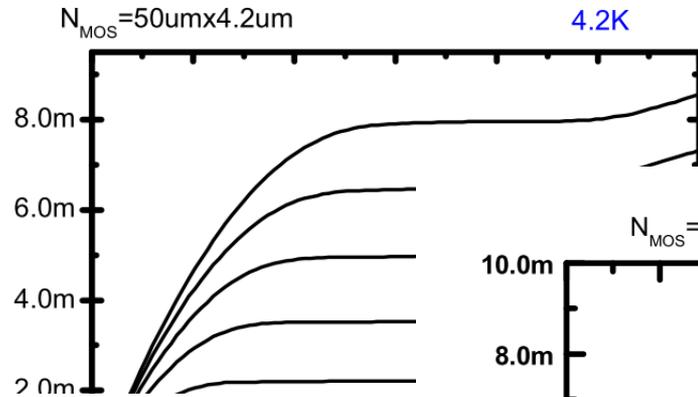
Ghibaudo, Balestra, "Low Temperature characterization of Silicon CMOS Devices", 1995

Y. Creten et al., IEEE J. Solid-State circuits, p. 2019 (2009)

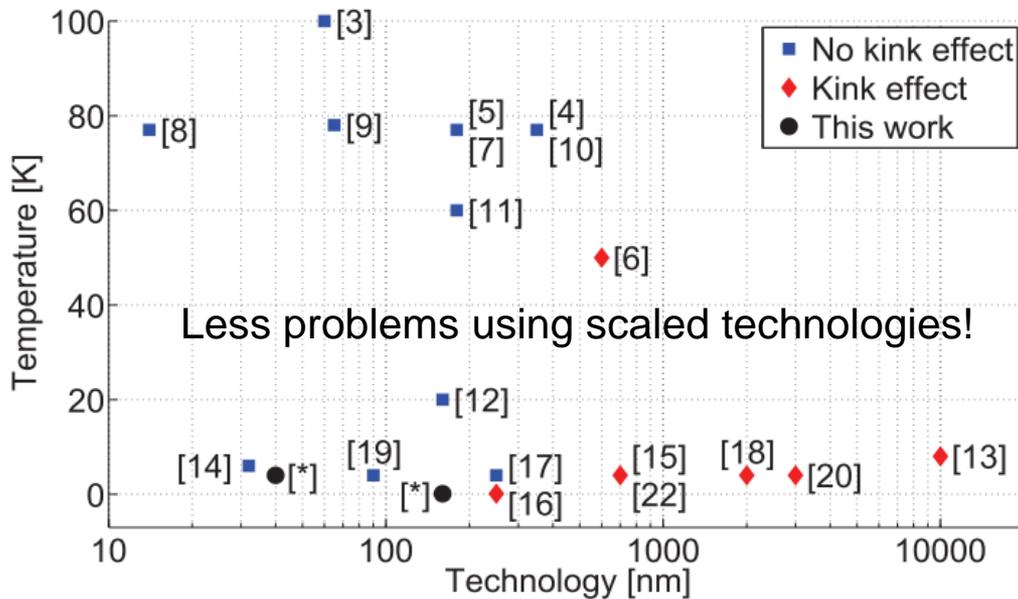
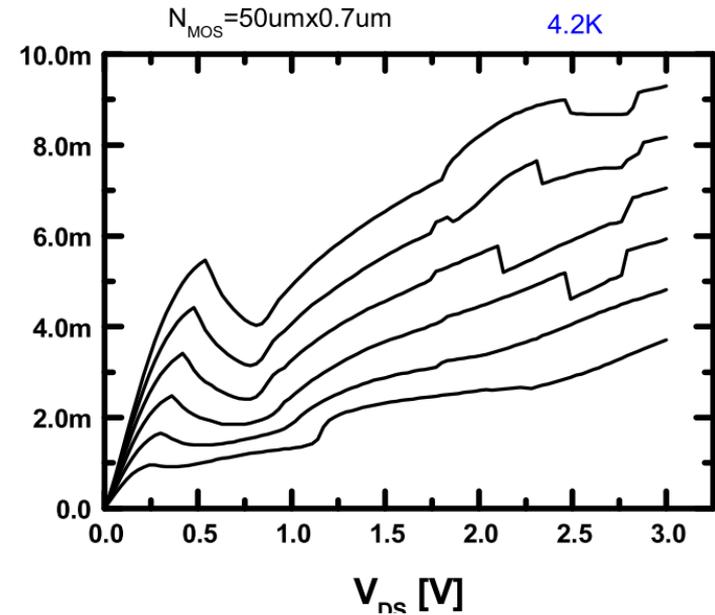
Problems are tech and size dependent



...and no models from the CMOS foundry!



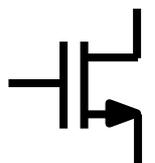
AMS 0.35 μ m



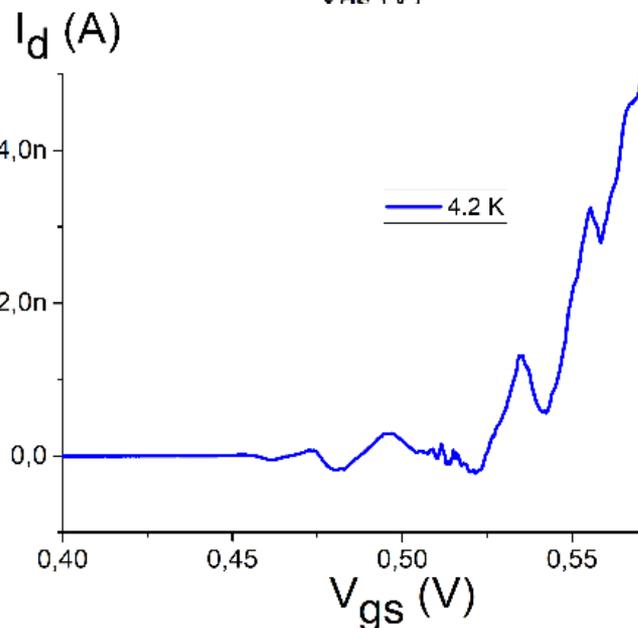
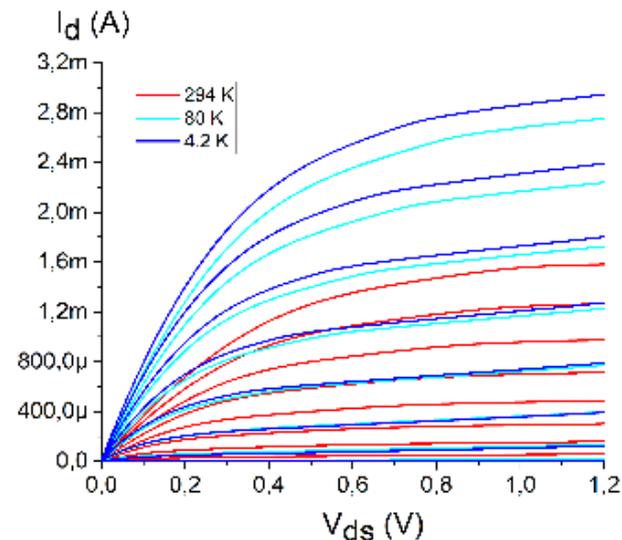
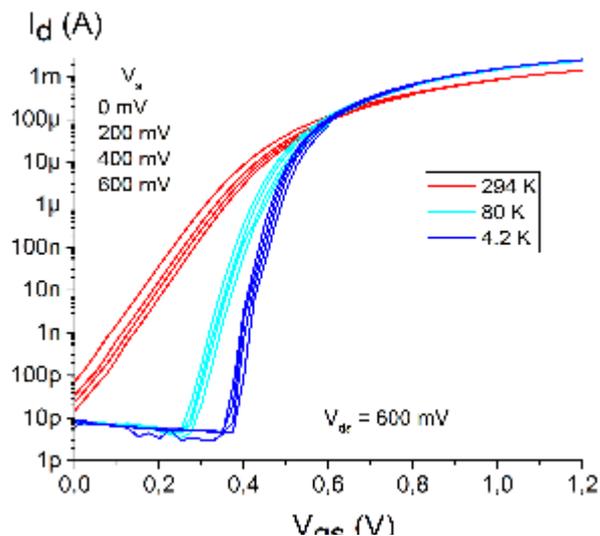
R. M. Incandela, et al., pp. 58–61, 2017 ESSDERC.

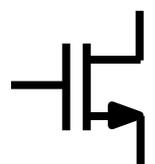
Quantum effects in small size MOSFETs!

110nm CMOS

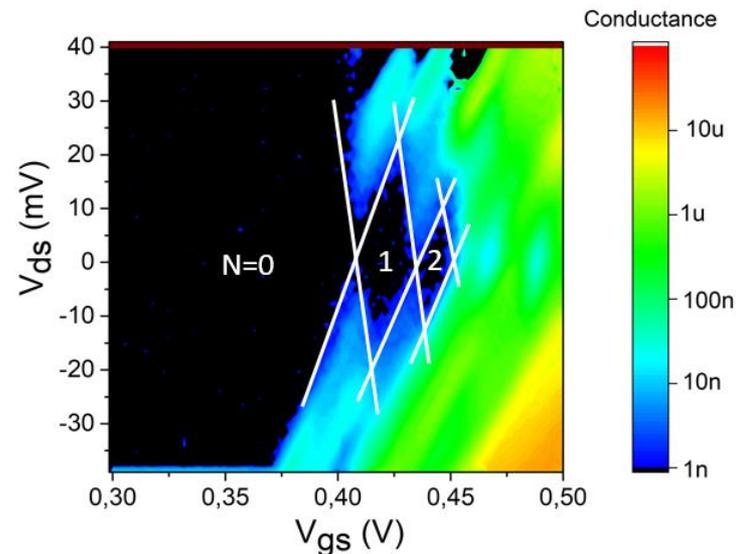


$$\frac{W}{L} = \frac{10\mu\text{m}}{0.5\mu\text{m}}$$





$$\frac{W}{L} = \frac{0.14\mu\text{m}}{0.1\mu\text{m}}$$



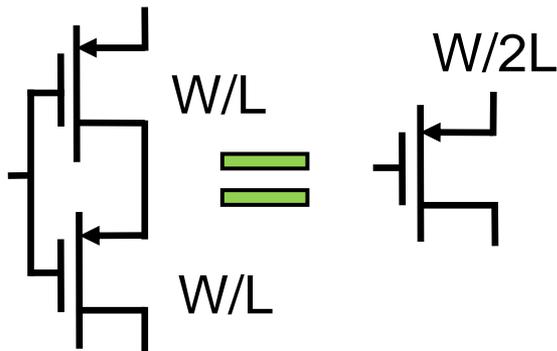
Design rule 1: characterize the technology!

MOS parameters strongly depend on the size and tech

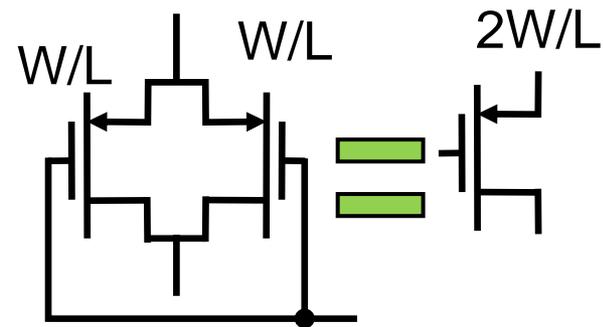


Experimental characterization of YOUR technology
is MANDATORY

For simple circuits 1 nMOS and 1 pMOS is enough
series or parallel combinations of these basic transistors

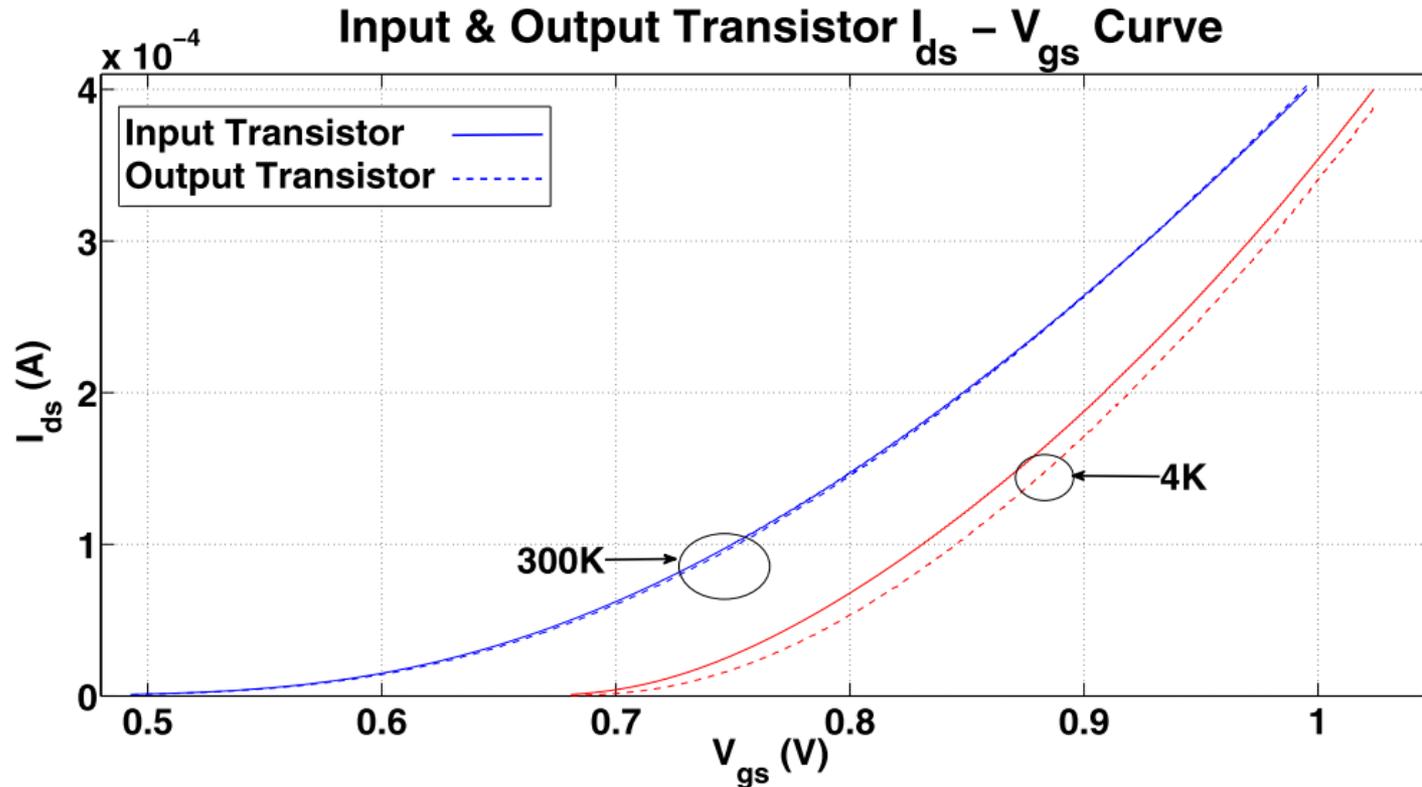


less conductive MOS



more conductive MOS

Design rule 2: pay attention to mismatch!



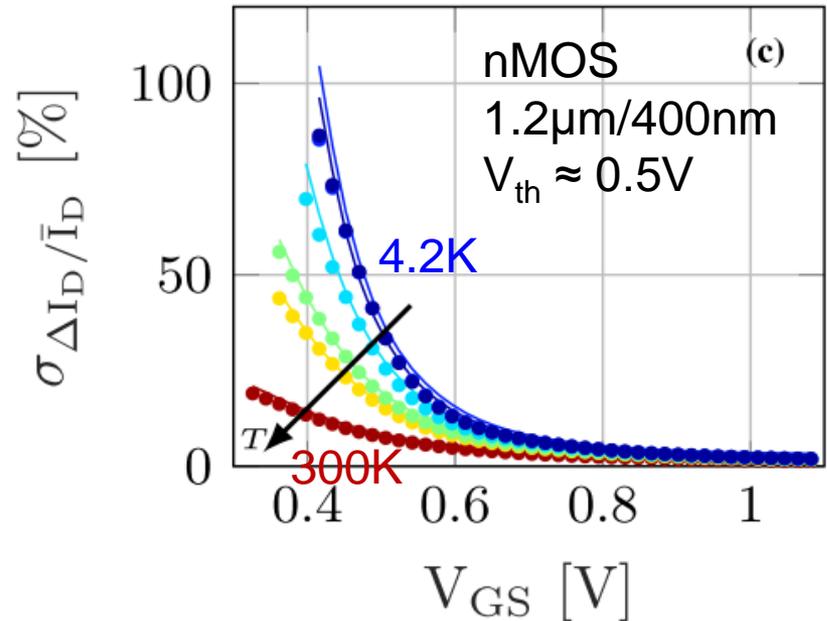
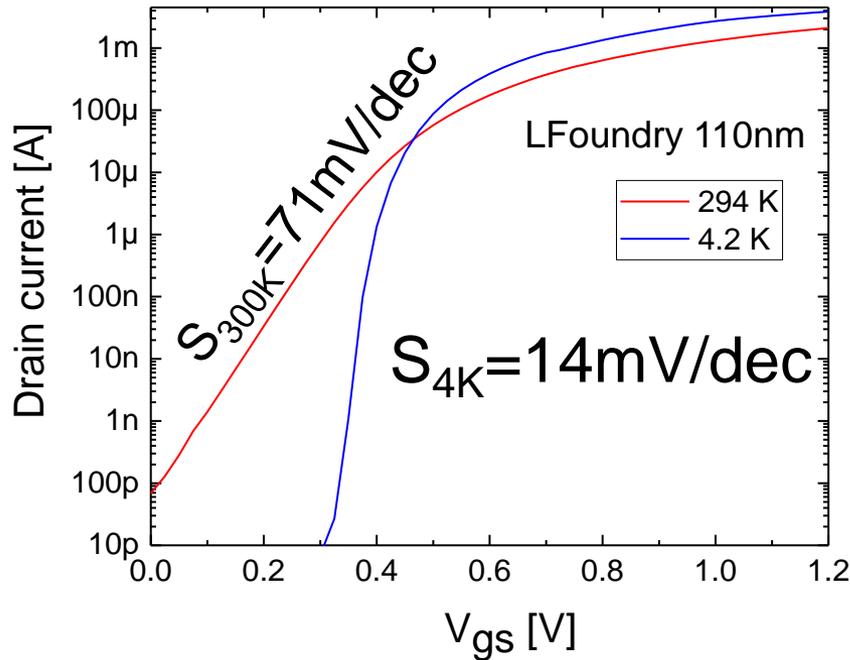
K. Das et al. EEE Symposium on Circuits and Systems, 2010

worsening of mismatch by a factor of 1.5-3 at low temperature compared to room temperature (tech dependent).



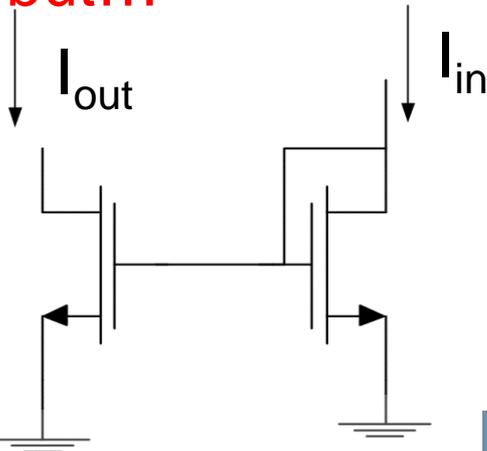
Degradation of the offset voltage, linearity of ADC, DAC, bias setting

Design rule 3: subthreshold is critical



P. A. T'Hart, et al. *IEEE J. Electron Devices Soc.*, pp. 263–273, 2020

Higher g_m and I_{on}/I_{off} , good!
but...



V_T mismatch of 5mV:

$$I_{out,300K} \approx I_{in} 10^{\frac{5mV}{S_{300K}}} = I_{in} \cdot 1.17$$

$$I_{out,4K} \approx I_{in} 10^{\frac{5mV}{S_{4K}}} = I_{in} \cdot 2.28$$

Design rule 4: dynamic range

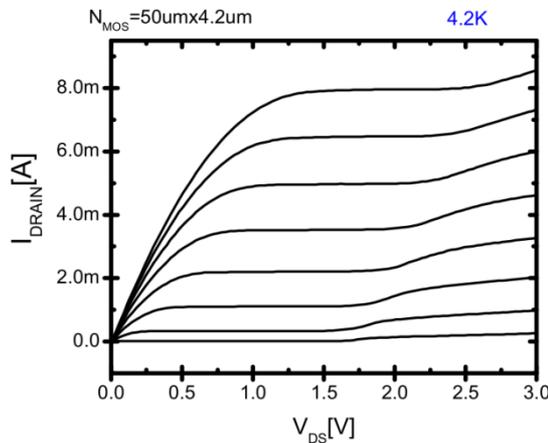
AMS 0.35 μm

- $V_{T,n}$ from 0.45V to 0.7V
- $V_{T,p}$ from -0.7V to -1.4V
- Power supply: 3.3V
- no subthreshold

stack up few transistors!

and

kink effect



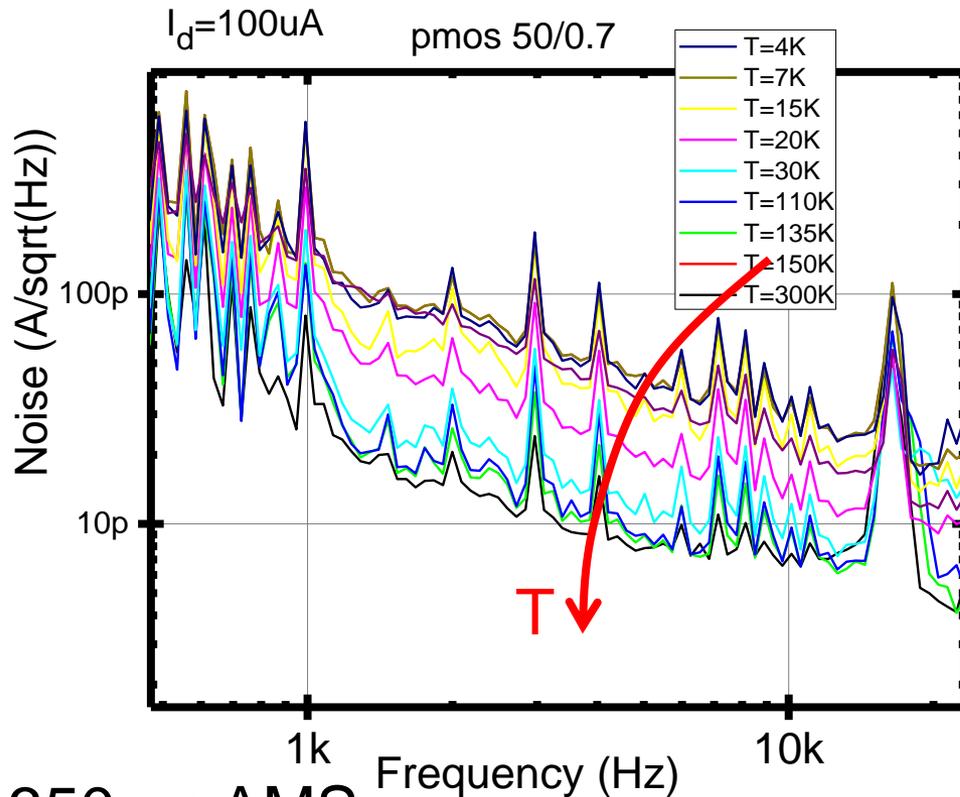
limit the V_{DS} !

Noise

Thermal noise: $\overline{e_n^2} = 4kT \frac{\gamma}{g_m}$

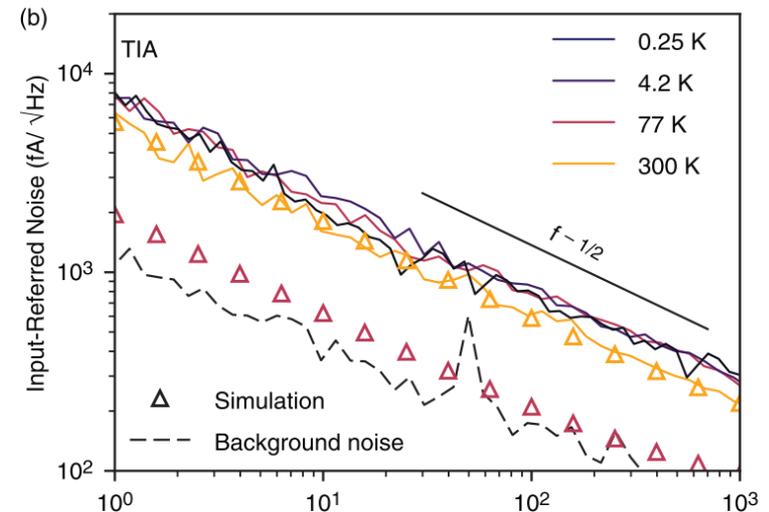
$T \searrow$, $g_m \nearrow \rightarrow$ **noise** $\searrow \searrow$
(0.1 nV/√Hz)

Flicker noise: increase or independent (tech and size dependent)



dominant noise up to tens of MHz

28nm FDSOI tech.



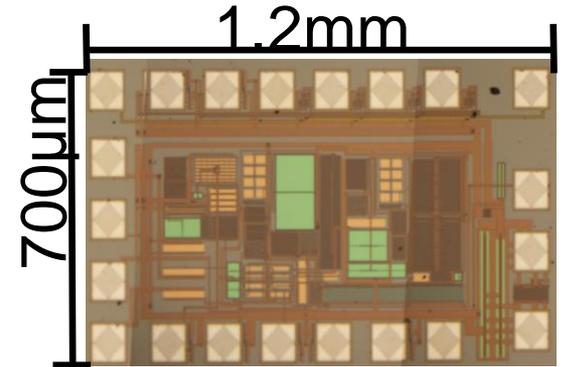
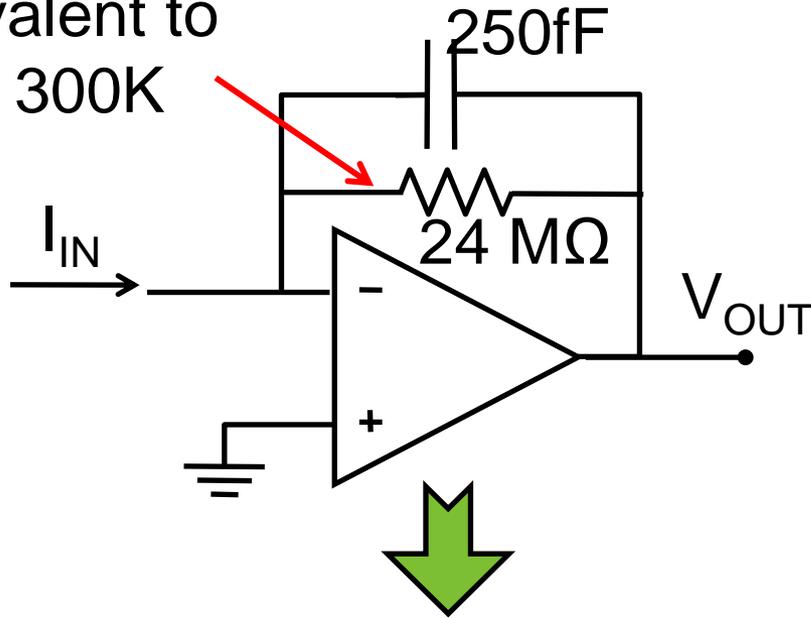
350nm AMS

Outline

- Spin detection using room temperature instrumentation
- Cryogenic electronics
 - Challenges
 - Design rules
- **Examples**

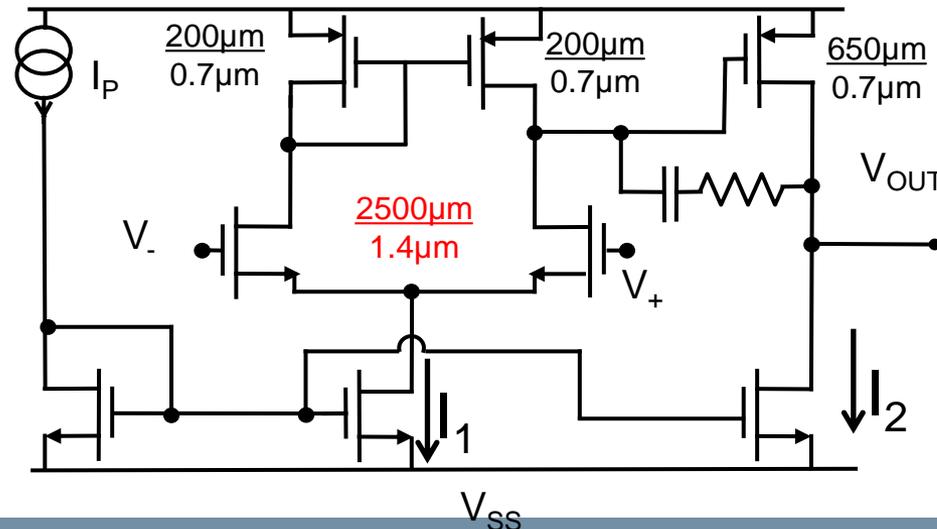
Cryogenic transimpedance amplifier

Noise equivalent to
 $1.7\text{G}\Omega$ @ 300K



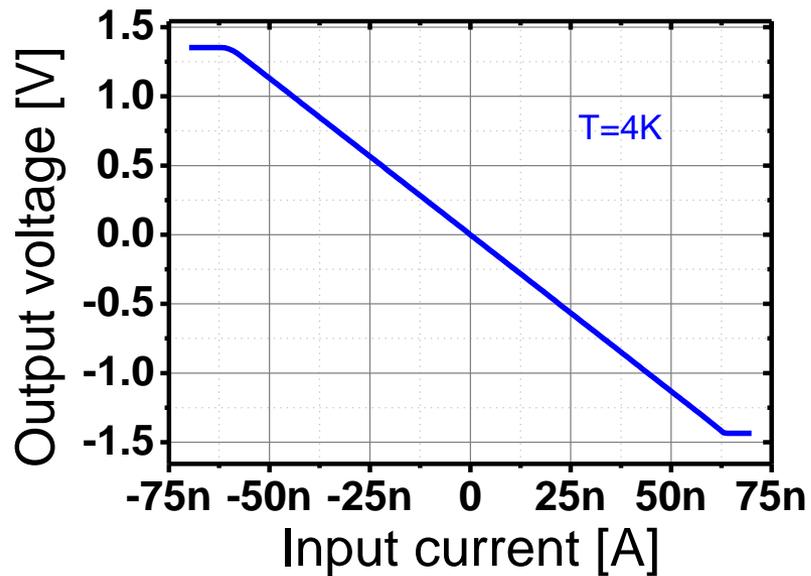
CMOS Technology
 3.3V $0.35\mu\text{m}$

nMos: $50\mu\text{m}/1.4\mu\text{m}$
pMos: $50\mu\text{m}/0.7\mu\text{m}$

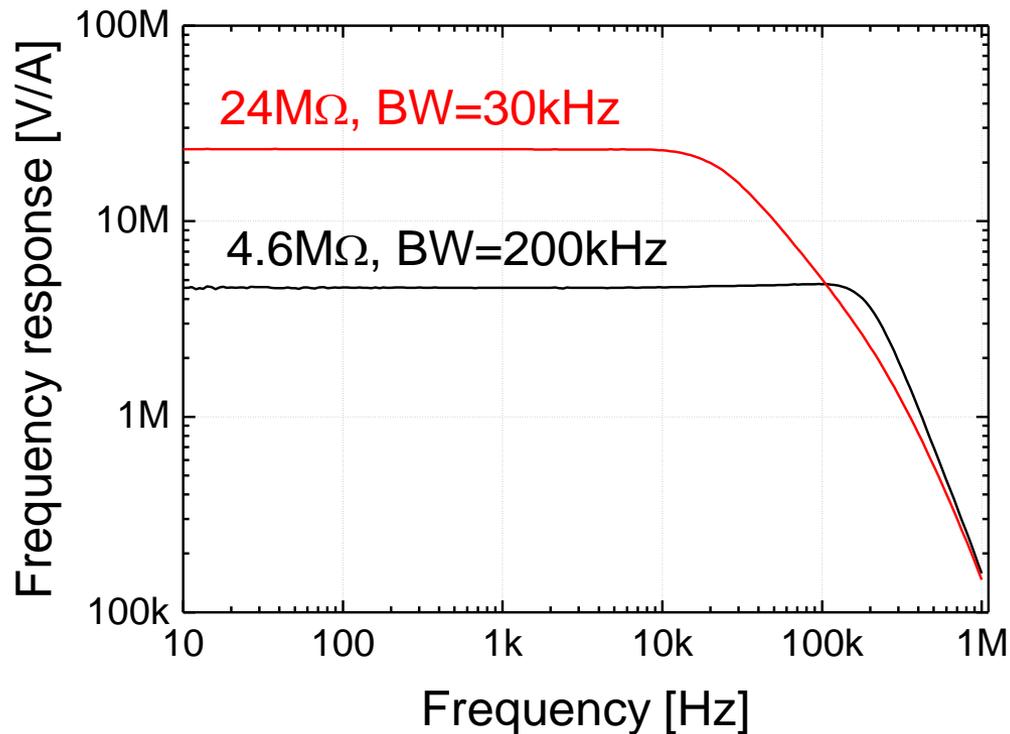


(simplified scheme)

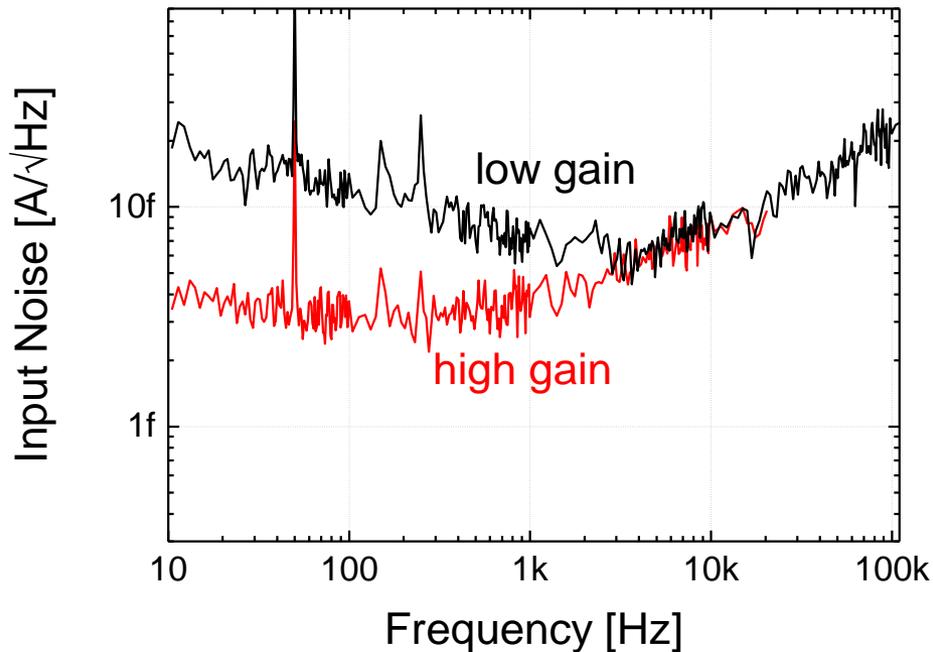
Measurements at 4 Kelvin



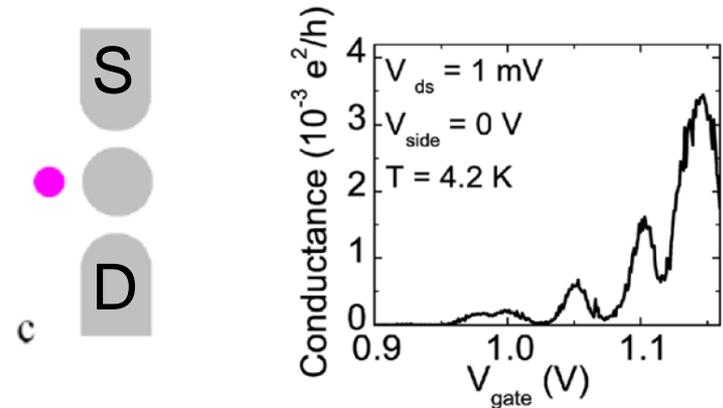
Gain, linearity and bandwidth match the simulations



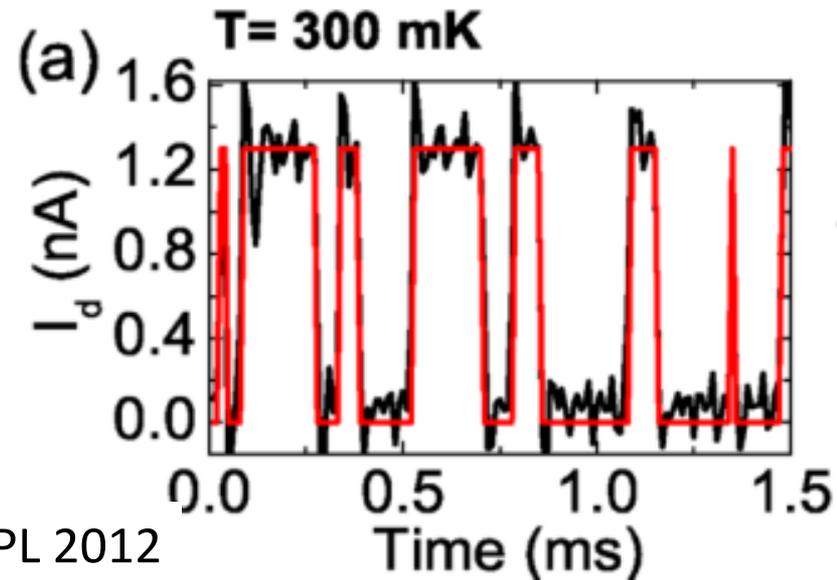
Measurements at 4 Kelvin



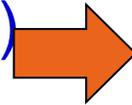
Quantum dots with a single ion implanted



Single charge state sensing

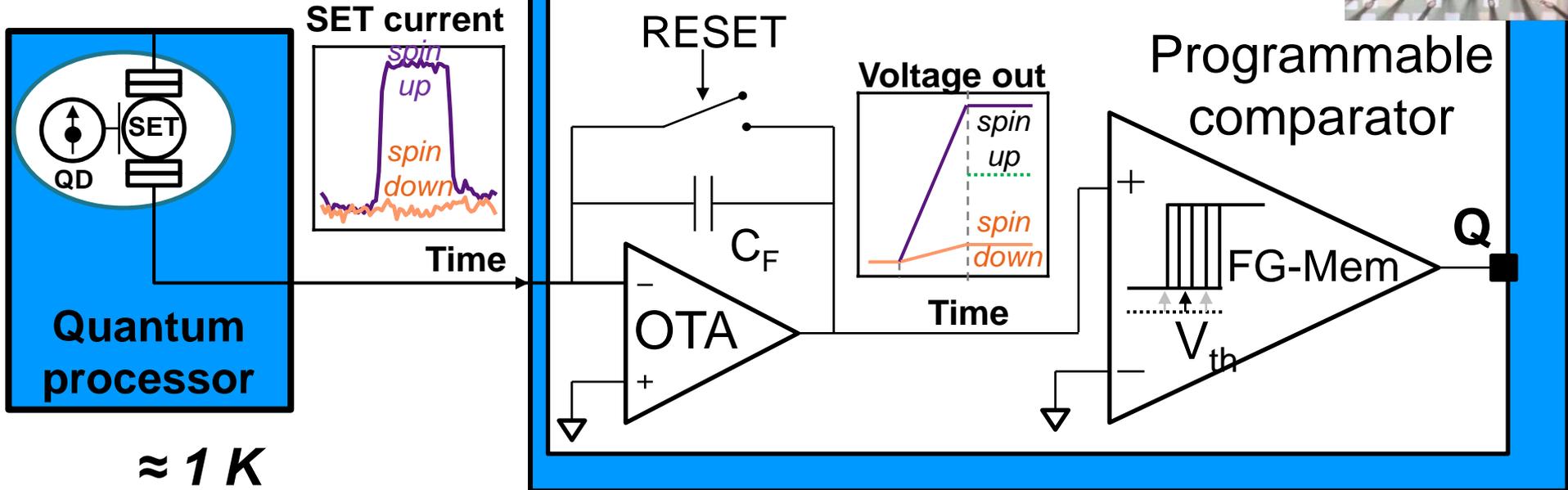


- 2.3 pA_{RMS} resolution (14 pA)
 - 32 kHz Bandwidth (190 kHz)
- ≈ 30 times better of RT



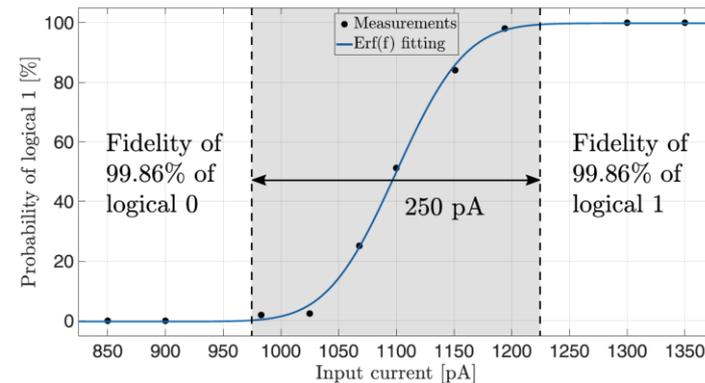
M. L. V. Tagliaferri et al, *IEEE Trans. Instrum. Meas.*, pp. 1827–1835, Aug. 2016.

Fully-integrated Cryo-CMOS readout of qubits

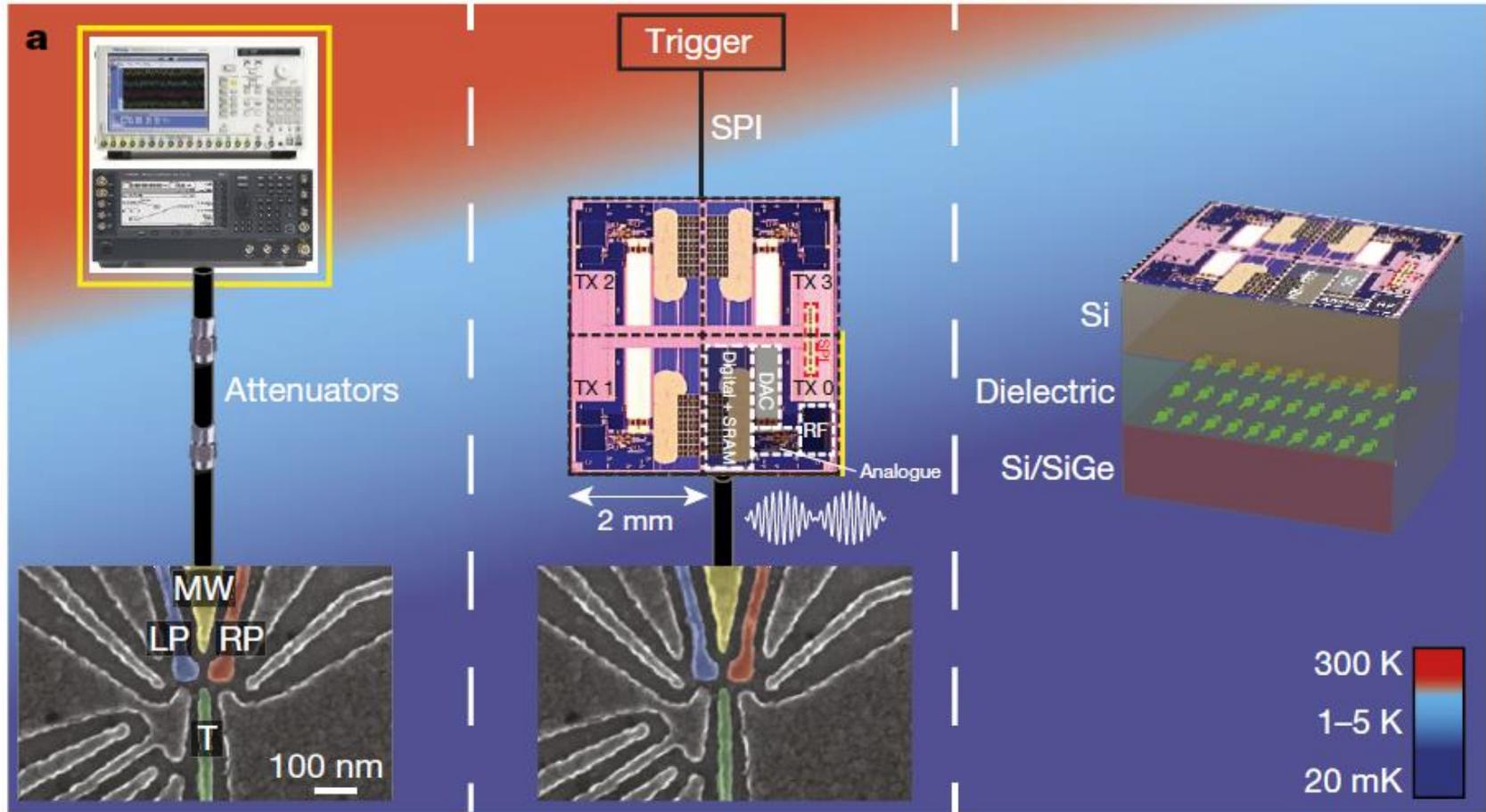


validated @ 4.2 K

- Direct current readout at 4.2K
- Readout in 500ns
- Power consumption = 1.2mW
- Area < 1 mm²
- Unconventional use of floating gates for a compact, programmable, and precise comparator (<1mV)



Cryogenic quantum controller



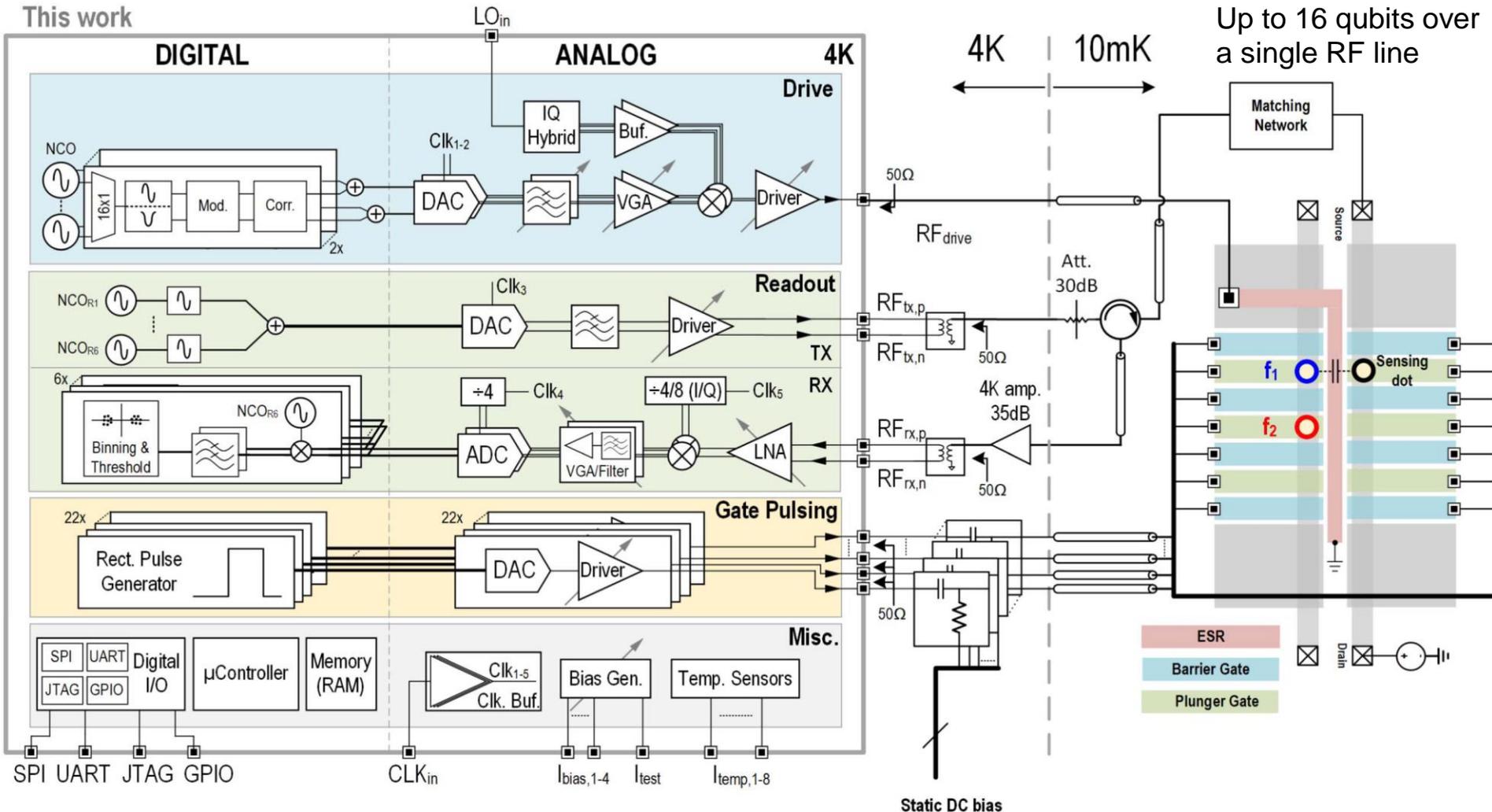
Today

Tomorrow

Future

X. Xue *et al.*, "CMOS-based cryogenic control of silicon quantum circuits," *Nature*, pp. 205–210, 2021

Intel quantum controller for spin qubits



J. Park, et al. ,“A Fully Integrated Cryo-CMOS SoC for State Manipulation, Readout, and High-Speed Gate Pulsing of Spin Qubits,” *IEEE J. Solid-State Circuits*, vol. 56, no. 11, pp. 3289–3306, 2021

Thank you for you attention!

